



TITLE: **IRA 404/07 - CSR18 Wafer run
Measurements**

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CHANGE RECORD

ISSUE	DATE	SHEET	DESCRIPTION	RELEASE
1.0	July. 27, 2007	1-58	First report drawing up	1.0
1.1	Sept. 20,2007		Added Spar and Noise parameters in Chapter 3 Chip count updated	

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1 - Introduction

In the following pages, we will describe results of the on wafer S-parameters and noise Temperature measurements. These have been performed on four 3-inch InP wafers, 75 μm thickness, processed by NGST, a division of NGC. The foundry process is a HEMT 0.1 μm gate length. Those four wafers are a part of a wafer run named CSR18, committed to NGST by CSIRO for the FARADAY consortium. Fig. 1.1 show the wafer run sharing percentage. The job had been carried out by IRA using the C-TIP Facilities in Epping, Sydney, Australia. With this campaign we have identified which devices are specification compliant and within this selection, which are the best, in term of noise temperature and gain. We haven't deeply investigated auto oscillations but the device behaviour didn't show any macroscopic evidence. Suspected response has been reported. Accurate oscillation enquiry as well as high accuracy noise temperature response, 1dB compression point value and 1/f noise characterization will be held on a limited number of samples. In the paper we will describe also the testing procedure adopted and the equipments used to compose the test-benches. In chapter 5, where measurement results are reported, we also suggest some hypothesis for future reverse engineering job. On those considerations we will base some electromagnetic simulation to discover possibly mutual coupling between large section of the stages that compose the MMIC. This activity will be very useful for future design activity. In order to understand the devices response far from the design conditions, some devices have been tested with design modified bias conditions and S-parameters responses are reported. This section will be completed with the noise temperature measurements of the same devices at the reported bias conditions. Table 2.1 show the design specifications of the LNA realized on the Wafer run CSR18.

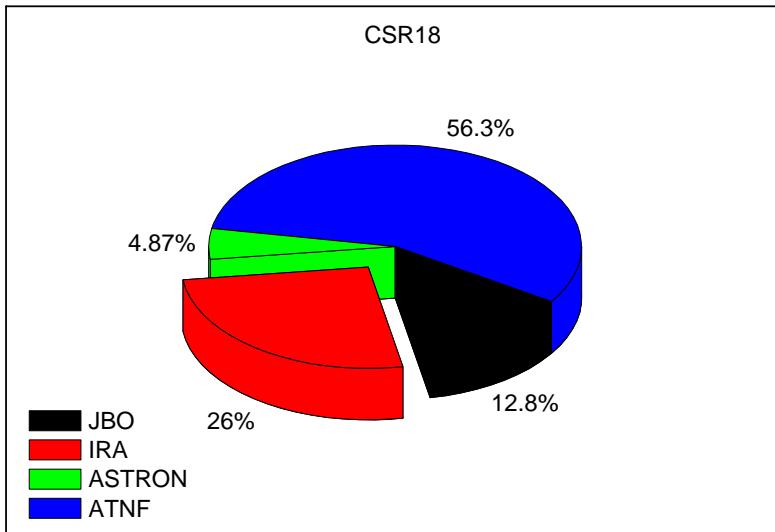


Fig 1.1 – Wafer run sharing percentage

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2 - Devices design specification

Design Name	Description	Frequency Range	Gain	Te @ 300 K	Te @ 20 K (estimated)	# stage	Power consumption (Nominal)	Dimension [mm]		# Working chip
		[GHz]	[dB]	[K]	[K]		[mW]	X	Y	
CSR18_6LNA_01A	LNA wout input matching network	4-8	35 ± 0.5	35	3	3	61,56	3,2	2,5	16/24
CSR18_10LNA_01A	LNA wout input matching network	8-12	22 ± 0.5	40	4	2	42,12	3,2	2,25	49/56
CSR18_32LNA_01A	LNA	26 - 40	23 ± 1	125	20	4	82,08	3,2	2,25	52/60
CSR18_32LNA_02A	LNA	26 - 40	25 ± 1	135	25	3	38,88	3,2	2,25	46/60
CSR18_43LNA_01A	LNA	33 - 50	27 ± 1.5	155	35	4	51,84	3,2	2,25	40/48
CSR18_86LNA_01A	LNA	70 - 90	17 ± 1	280	60	4	76,14	3,2	2,25	41/52
CSR18_100LNA_01A	LNA	90 - 115	15 ± 1	400	100	4	52,68	2,5	2,5	17/24

Table 2.1 - Devices design specification

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Tests have been carried out following the instructions listed in Table 2.2. For the devices a,b we haven't measured the noise because they have been designed with an off-chip matching network for the first stage. Noise performances of the c,d,e devices have been tested up to 39 GHz due to a limit of the Facilities. For the same reason, device g have been tested up to 98 GHz. All the automatic measurements have been conducted using the design bias condition. These are reported in table 2.3.

	Design Name	Spar			Noise		
		Fmin [GHz]	Fmax [GHz]	N. of points	Fmin	Fmax [GHz]	step
a	CSR18_6LNA_01A	1	10	51	X	X	X
b	CSR18_10LNA_01A	5	15	51	X	X	X
c	CSR18_32LNA_01A	20	50	51	26	39	1
d	CSR18_32LNA_02A	20	50	51	26	39	1
e	CSR18_43LNA_01A	20	50	51	33	39	1
f	CSR18_86LNA_01A	70	118	101	75	90	1
g	CSR18_100LNA_01A	70	118	101	84	98	1

Table 2.2 – Test schedule

INAF  <small>ISTITUTO NAZIONALE DI ASTROFISICA NATIONAL INSTITUTE FOR ASTROPHYSICS</small>	Doc. Title:	IRA 404/07 - CSR18 Wafer run Measurements	
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Design Name	D1		D2		D3		D4	
	Vd [V]	Id [mA]	Vd [V]	Id mA	Vd [V]	Id mA	Vd [V]	Id mA
CSR18_6LNA_01A	1,26	18	X	X	1,08	18	1,08	18
CSR18_10LNA_01A	1,26	18	1,08	18	X	X	X	X
CSR18_32LNA_01A	1,2	12	1,32	12	1,44	18	1,44	18
CSR18_32LNA_02A	1,08	12	X	X	1,08	12	1,08	12
CSR18_43LNA_01A	1,08	12	1,08	12	1,08	12	1,08	12
CSR18_86LNA_01A	1,08	12	1,17	18	1,17	18	1,17	18
CSR18_100LNA_01A	1,24	12	1,3	12	1,3	12	1,1	6

Table 2.3 – Devices nominal biasing

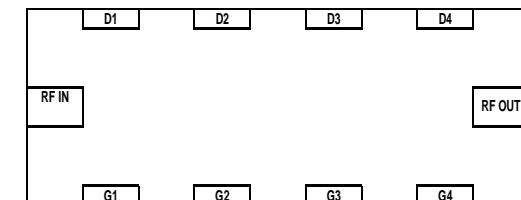


Fig. 2.1 – Bias and RF pad Layout

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3 – Datasheets

In order to clarify some datasheet entries we here describe its meaning little widely :

The definition of **Frequency Range**, as reported in the datasheets, isn't exactly related with the theoretical definition of bandwidth @3dB. Some other factors than gain response, like IRL and Te has influence on this definition.

σ indicate the well known standard deviation, which represent the statistical dispersion of values in a given dataset, measuring how widely spread the values in a dataset are.

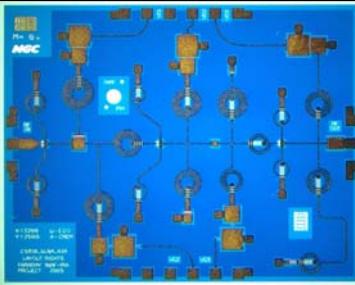
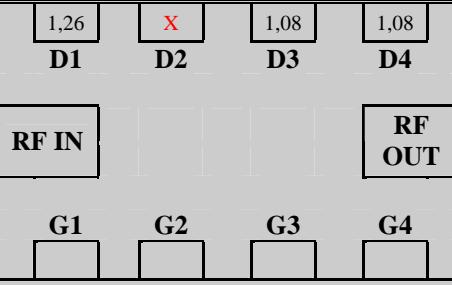
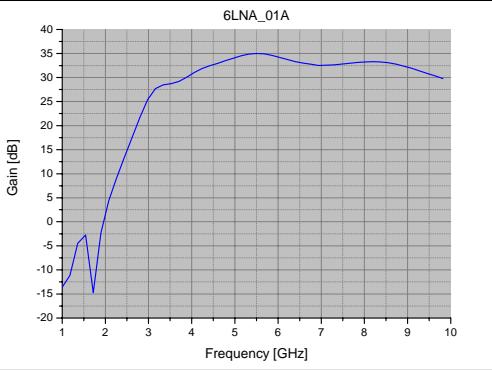
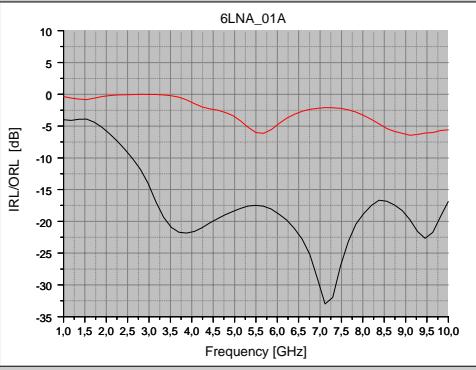
Bandwidth
$$BW = f_2 - f_1 \quad (1)$$

Center Frequency
$$f_0 = \sqrt{f_2 \cdot f_1} \quad (2)$$

Fractional Bandwidth
$$\frac{BW}{f_0} \cdot 100 \quad (3)$$

For system design purposes, typical measured S-parameters and simulated Noise parameters are reported for each MMIC design.

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P/N	6LNA_01A			
Rev Date	20/6/2007			
				
				
Frequency Range	4 - 10	BW	6	BW/f ₀
100% BW Performance Summary			50% BW Performance Summary	
	Value	σ	Value	σ
	min	max	typ	min
Gain	30,8	33,8	32,9	30,2
T_e	-	-	-	-
 S₁₁ 	-3,6	-2,8	-3,3	-4,5
 S₂₂ 	-23,4	-19,4	-21,3	-23,5
IP₃				
Dissipation [mW]	62			
RF Pad	Coplanar G-S-G 200 μ m pitch			
Bias Pad	Coplanar G-SSSS-G 200 μ m pitch			
Dimensions	3.200 x 2.500 x 0.075 mm (L x W x H)			
Use as	Designed for Pharos receiver. possibly use in medicina and SRT receivers with HTS filters			
Particularity	Off-chip first stage input matching network. Performances reported in this datasheet are related to the MMIC ONLY. For more exhaustive information regarding the combined use with the external matching network, please refer to chapter 5 of IRA Internal Report N.			
N° of available samples	16/24			

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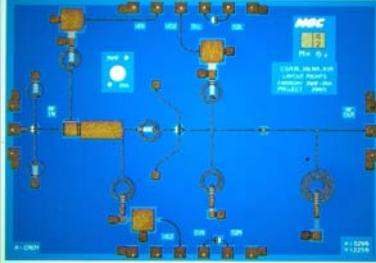
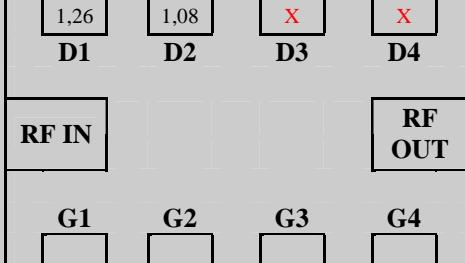
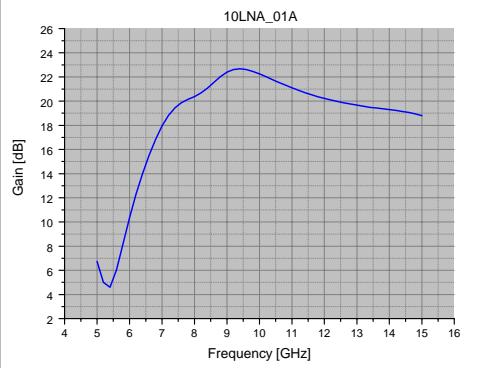
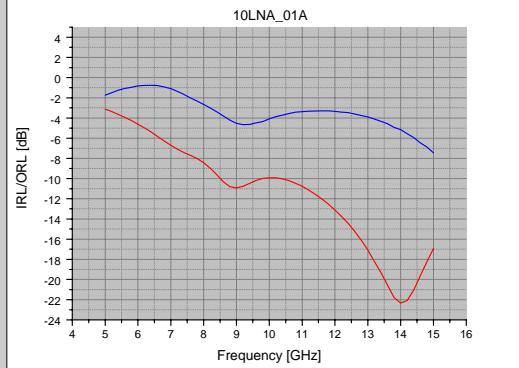
Noise Parameters

Freq [GHz]	NFmin [dB]	Γ _{opt}	φ(Γ _{opt})	Rn
3,5	0,17148	0,89126	17,8411	0,31933
3,6	0,1753	0,88674	18,2411	0,31124
3,7	0,17846	0,88261	18,6105	0,30365
3,8	0,18083	0,87897	18,9552	0,29675
3,9	0,18248	0,87584	19,2882	0,29067
4,0	0,18362	0,87312	19,624	0,28543
4,1	0,18519	0,87062	19,9734	0,28166
4,2	0,1868	0,86814	20,34	0,27837
4,3	0,18861	0,86555	20,7234	0,27538
4,4	0,19067	0,86279	21,1201	0,27257
4,5	0,193	0,85984	21,5259	0,26984
4,6	0,19607	0,85675	21,941	0,26767
4,7	0,19933	0,85352	22,3575	0,26551
4,8	0,20272	0,85019	22,7734	0,26337
4,9	0,20622	0,8468	23,1873	0,26124
5,0	0,20976	0,84336	23,5985	0,25913
5,1	0,21406	0,83998	23,9997	0,25795
5,2	0,21837	0,83661	24,3975	0,2568
5,3	0,22268	0,83325	24,7922	0,25569
5,4	0,22696	0,82992	25,1841	0,2546
5,5	0,2312	0,82663	25,5739	0,25354
5,6	0,23572	0,82336	25,9617	0,25269
5,7	0,24018	0,82013	26,3481	0,25187
5,8	0,24457	0,81694	26,7337	0,25106
5,9	0,24888	0,8138	27,1192	0,25024
6,0	0,2531	0,8107	27,5053	0,24942
6,1	0,25754	0,80764	27,8912	0,24892
6,2	0,26189	0,80462	28,2785	0,24838
6,3	0,26615	0,80161	28,6675	0,24781
6,4	0,2703	0,79861	29,0587	0,24718
6,5	0,27434	0,79563	29,4525	0,2465
6,6	0,27903	0,79264	29,8429	0,2462
6,7	0,28365	0,78964	30,2353	0,24583
6,8	0,2882	0,78663	30,6299	0,24539
6,9	0,29267	0,7836	31,0268	0,24487
7,0	0,29706	0,78055	31,4262	0,24425
7,1	0,30184	0,77739	31,8233	0,24382
7,2	0,30657	0,77419	32,2218	0,2433
7,3	0,31127	0,77092	32,6216	0,24268
7,4	0,31593	0,76759	33,0226	0,24196
7,5	0,32055	0,76419	33,4246	0,24112
7,6	0,32545	0,76071	33,8187	0,24034
7,7	0,33034	0,75716	34,212	0,23947
7,8	0,33523	0,75353	34,6041	0,23852
7,9	0,34013	0,74982	34,9947	0,23748
8,0	0,34505	0,74601	35,3831	0,23636
8,1	0,35047	0,74213	35,7571	0,23553
8,2	0,35597	0,73815	36,1263	0,23464
8,3	0,36153	0,73406	36,4899	0,23368
8,4	0,36719	0,72986	36,8467	0,23268
8,5	0,37295	0,72554	37,1957	0,23162

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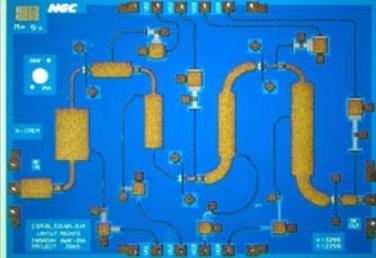
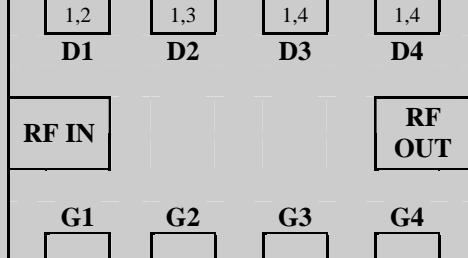
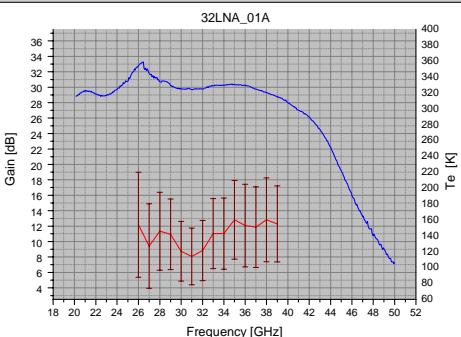
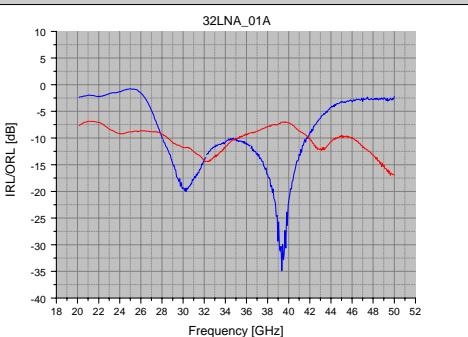
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Frequency Range 8 - 13	BW 5	BW/f_o 49%																																																																	
100% BW Performance Summary		50% BW Performance Summary																																																																	
<table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th rowspan="2"></th> <th colspan="3">Value</th> <th rowspan="2">σ</th> <th rowspan="2">Units</th> </tr> <tr> <th>min</th> <th>max</th> <th>typ</th> </tr> </thead> <tbody> <tr> <td>Gain</td> <td>20,2</td> <td>21,9</td> <td>21</td> <td>0,9</td> <td>[dB]</td> </tr> <tr> <td>T_e</td> <td>-</td> <td>-</td> <td>-</td> <td></td> <td>[K]</td> </tr> <tr> <td> s₁₁ </td> <td>-4,4</td> <td>-3,4</td> <td>-3,9</td> <td>0,7</td> <td>[dB]</td> </tr> <tr> <td> s₂₂ </td> <td>-12,2</td> <td>10,2</td> <td>-10,7</td> <td>1</td> <td>[dB]</td> </tr> </tbody> </table>		Value			σ	Units	min	max	typ	Gain	20,2	21,9	21	0,9	[dB]	T_e	-	-	-		[K]	s ₁₁	-4,4	-3,4	-3,9	0,7	[dB]	s ₂₂	-12,2	10,2	-10,7	1	[dB]	<table border="1" style="width: 100%; border-collapse: collapse;"> <thead> <tr> <th rowspan="2"></th> <th colspan="3">Value</th> <th rowspan="2">σ</th> <th rowspan="2">Units</th> </tr> <tr> <th>min</th> <th>max</th> <th>typ</th> </tr> </thead> <tbody> <tr> <td>Gain</td> <td>20,8</td> <td>22,5</td> <td>21,6</td> <td>0,6</td> <td>[dB]</td> </tr> <tr> <td>T_e</td> <td>-</td> <td>-</td> <td>-</td> <td>-</td> <td>[K]</td> </tr> <tr> <td> s₁₁ </td> <td>-4,7</td> <td>-3,8</td> <td>-4,2</td> <td>0,6</td> <td>[dB]</td> </tr> <tr> <td> s₂₂ </td> <td>-11,7</td> <td>-10,1</td> <td>-10,5</td> <td>0,3</td> <td>[dB]</td> </tr> </tbody> </table>		Value			σ	Units	min	max	typ	Gain	20,8	22,5	21,6	0,6	[dB]	T_e	-	-	-	-	[K]	s ₁₁	-4,7	-3,8	-4,2	0,6	[dB]	s ₂₂	-11,7	-10,1	-10,5	0,3	[dB]
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s ₂₂	-11,7	-10,1	-10,5	0,3	[dB]																																																														
IP₃																																																																			
Dissipation [mW]	42																																																																		
RF Pad	Coplanar G-S-G 200 μ m pitch																																																																		
Bias Pad	Coplanar G-SSSS-G 200 μ m pitch																																																																		
Dimensions	3.200 x 2.550 x 0.075 mm (L x W x H)																																																																		
Use as	For holography applications																																																																		
Particularity	Off-chip first stage input matching network. Performances reported in this datasheet are related to the MMIC ONLY. For more exhaustive information regarding the combined use with the external matching network, please refer to chapter 5 of IRA Internal Report N.																																																																		
N° of available samples	49/56																																																																		

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Noise Parameters

Freq [GHz]	NFmin [dB]	 Γ_{opt} 	φ(Γ_{opt})	Rn
5,0	1,20591	0,85907	18,2445	1,14684
5,5	0,89752	0,87705	20,2816	1,00109
6,0	0,45506	0,86848	22,7129	0,53666
6,5	0,33982	0,84571	24,8723	0,37663
7,0	0,31411	0,82192	26,755	0,31146
7,5	0,31505	0,79993	28,4706	0,27804
8,0	0,32459	0,7805	30,0544	0,25824
8,5	0,33535	0,76341	31,5572	0,24477
9,0	0,34782	0,74796	33,0115	0,23544
9,5	0,36394	0,73365	34,4872	0,22967
10,5	0,40074	0,708	37,5025	0,22349
10,5	0,40113	0,70775	37,5338	0,22345
11,0	0,41991	0,69554	39,1415	0,22103
11,5	0,44078	0,68322	40,8091	0,21927
12,0	0,46251	0,67042	42,5055	0,21714
12,5	0,48427	0,65755	44,1719	0,21546
13,0	0,50885	0,64333	45,8562	0,21339
13,5	0,53397	0,62811	47,5484	0,21065
14,0	0,55971	0,61059	49,2725	0,20659
14,5	0,58634	0,59064	51,0719	0,20067
15,0	0,60874	0,56794	52,8573	0,19275

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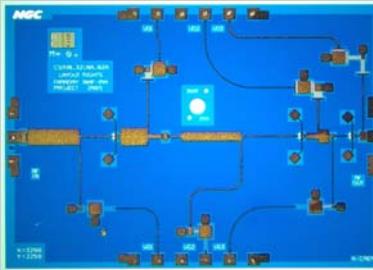
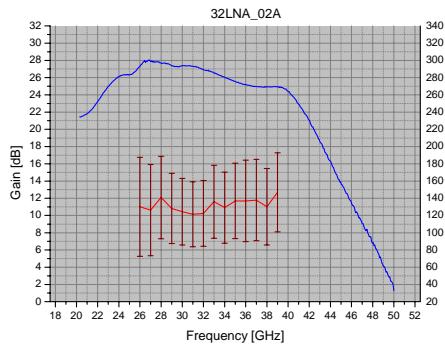
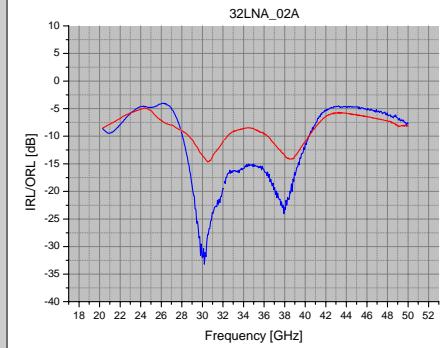
P/N	32LNA_01A				
Rev Date	20/6/2007				
					
					
Frequency Range	26 - 40	BW	14	BW/f_o	43%
100% BW Performance Summary		50% BW Performance Summary			
Gain	28	32	30	1,3	[dB]
T_e	139	156	145	10	[K]
 S₁₁ 	-14, 5	-12,8	-13,5	6,5	[dB]
 S₂₂ 	-11,4	-8,9	-10,0	2	[dB]
IP₃					
Dissipation [mW]					
RF Pad		Coplanar G-S-G 200 μm pitch			
Bias Pad		Coplanar G-SSSS-G 200 μm pitch			
Dimensions		3.200 x 2.550 x 0.075 mm (L x W x H)			
Use as		Cryogenic Front end LNA for ground-based radioastronomy applications; Uncooled LNA for noise measurement applications			
Particularity		4 stage separately biased LNA			
N° of available samples		52/60			

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Noise Parameters

Freq [GHz]	NFmin [dB]	$ \Gamma_{\text{opt}} $	$\varphi(\Gamma_{\text{opt}})$	Rn
16	7,77295	0,40601	-132,511	1,0682
17	5,16779	0,22471	-149,128	0,51353
18	3,6257	0,28056	177,143	0,25496
19	2,77885	0,40421	176,305	0,1391
20	2,30427	0,49275	-175,306	0,0898
21	2,00413	0,54397	-164,52	0,07813
22	1,78424	0,56442	-152,637	0,09117
23	1,63411	0,56115	-139,959	0,11991
24	1,54116	0,53947	-126,389	0,15684
25	1,48269	0,50233	-111,689	0,19479
26	1,44322	0,45223	-95,6524	0,22694
27	1,41641	0,39308	-78,1528	0,24836
28	1,40202	0,33128	-59,1278	0,25777
29	1,40173	0,27477	-38,5353	0,2575
30	1,41524	0,2304	-16,4664	0,25131
31	1,44012	0,20134	6,38008	0,24226
32	1,47306	0,18606	28,5141	0,23189
33	1,50931	0,1797	48,4805	0,22062
34	1,5453	0,17613	65,7299	0,20863
35	1,57934	0,16988	80,4268	0,19662
36	1,61054	0,15653	92,858	0,1861
37	1,63888	0,13248	102,811	0,17953
38	1,66541	0,09524	107,909	0,18037
39	1,69267	0,04907	90,3819	0,19324
40	1,72518	0,06502	16,6568	0,2239
41	1,76963	0,15669	7,0071	0,27916
42	1,83467	0,27138	14,9413	0,36632
43	1,93047	0,39382	26,7849	0,49241
44	2,06805	0,51024	39,5916	0,6634
45	2,25877	0,61008	52,0804	0,88347
46	2,51374	0,68891	63,6062	1,1545
47	2,84256	0,74762	73,9239	1,47541
48	3,25106	0,78971	83,0285	1,84106
49	3,7382	0,81913	91,0276	2,24091
50	4,29363	0,83929	98,0653	2,65791

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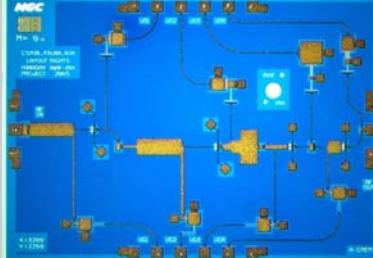
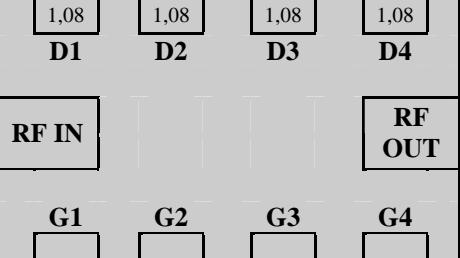
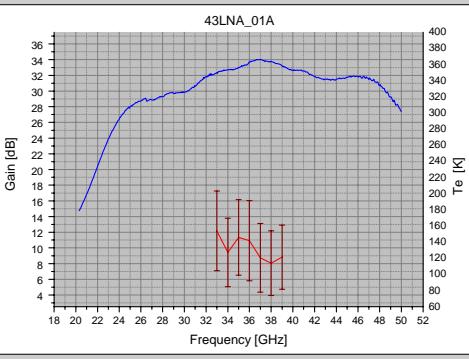
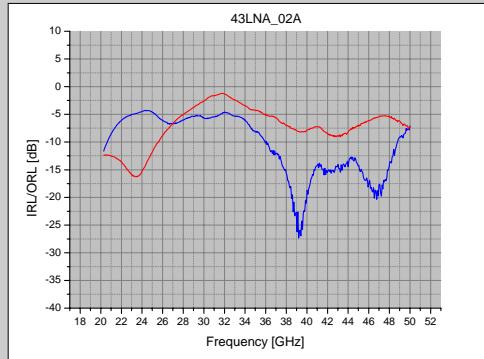
P/N	32LNA_02A				
Rev Date	20/6/2007				
	D1	D2	D3	D4	
	RF IN		RF OUT		
	G1	G2	G3	G4	
					
Frequency Range	26 - 40				
100% BW Performance Summary					
	Value	σ	Units		
	min			max	typ
Gain	24,7	27,7	25,8	1,3	[dB]
T_e	125	152	140	5	[K]
 S₁₁ 	-19,4	-11,5	-16,3	6	[dB]
 S₂₂ 	-12	-8,8	-10,7	2	[dB]
IP₃					
Dissipation [mW]					
RF Pad					
Bias Pad					
Dimensions					
Use as					
Particularity					
N° of available samples					
43%					
50% BW Performance Summary					
	Value	σ	Units		
	min			max	typ
Gain	24,6	27,8	25,9	0,9	[dB]
T_e	122	149	137	5	[K]
 S₁₁ 	-23,5	-11,9	-18,3	2	[dB]
 S₂₂ 	-12	-8,8	-10,7	2	[dB]
40					
Coplanar G-S-G 200 μ m pitch					
Coplanar G-SSSS-G 200 μ m pitch					
3.200 x 2.550 x 0.075 mm (L x W x H)					
Cryogenic Front end LNA for ground-based radioastronomy applications; Uncooled LNA are also used for IRA receiver noise measurements					
3 stage separately biased LNA					
46/60					

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Noise Parameters

Freq [GHz]	NFmin [dB]	$ \Gamma_{opt} $	$\varphi(\Gamma_{opt})$	Rn
16	12,7769	0,8195	-164,547	1,32311
17	9,50899	0,76875	-148,723	1,49562
18	6,24006	0,6654	-130,968	1,01619
19	4,39029	0,52153	-110,777	0,73658
20	3,33732	0,35645	-86,4927	0,56259
21	2,71726	0,20486	-52,0535	0,44107
22	2,28222	0,13007	8,6119	0,34484
23	1,96211	0,16855	66,6116	0,26913
24	1,74672	0,23648	96,7802	0,21022
25	1,58731	0,28843	116,487	0,16189
26	1,45257	0,31604	132,08	0,12394
27	1,35574	0,32272	145,093	0,0993
28	1,30661	0,31466	155,996	0,08691
29	1,29473	0,29754	165,097	0,08319
30	1,30836	0,27482	172,876	0,08511
31	1,33951	0,248	179,638	0,09097
32	1,38026	0,21845	-174,487	0,09948
33	1,42381	0,18706	-169,368	0,10971
34	1,46484	0,15403	-164,861	0,12109
35	1,4993	0,11878	-160,884	0,13333
36	1,52462	0,08011	-157,827	0,14644
37	1,54024	0,03668	-159,885	0,1606
38	1,54849	0,01795	70,6999	0,17611
39	1,55612	0,07577	55,1762	0,19328
40	1,57655	0,14401	60,9513	0,2124
41	1,6331	0,21915	70,1946	0,23367
42	1,7626	0,29591	81,4062	0,25722
43	2,01772	0,36684	93,8414	0,2834
44	2,46626	0,42507	106,748	0,31326
45	3,18788	0,46686	119,43	0,34999
46	4,27423	0,4916	131,422	0,40255
47	5,8352	0,49986	142,537	0,49545
48	8,04365	0,49187	152,779	0,70667
49	11,3031	0,46684	162,193	1,36748
50	16,7893	0,42214	170,561	4,96845

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P/N	43LNA_01A										
Rev Date	20/6/2007										
											
											
Frequency Range	31 - 48										
	BW 17 BW/f_o 44%										
100% BW Performance Summary					50% BW Performance Summary						
	Value			σ	Units		Value			σ	Units
	min	max	typ				min	max	typ		
Gain	29,5	33,2	31,6	1,7	[dB]	Gain	29,7	33,6	31,8	0,9	[dB]
T_e	157	198	172	6	[K]	T_e	-	-	-	-	[K]
 S₁₁ 	-15,2	4,1	-8,4	4	[dB]	 S₁₁ 	-16,9	-10,4	-15,2	2	[dB]
 S₂₂ 	-7,4	0,6	-4,5	1,4	[dB]	 S₂₂ 	-8,5	-7,2	-8	0,6	[dB]
IP₃											
Dissipation [mW]											
52											
Coplanar G-S-G 200 μm pitch											
Coplanar G-SSSS-G 200 μm pitch											
Dimensions											
3.200 x 2.550 x 0.075 mm (L x W x H)											
Cryogenic Front end LNA for ground-based radioastronomy applications; Uncooled LNA are also used for IRA receiver noise measurements											
4 stage separately biased LNA											
N° of available samples											
40/52											

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Noise Parameters

Freq [GHz]	NFmin [dB]	$ \Gamma_{\text{opt}} $	$\varphi(\Gamma_{\text{opt}})$	Rn
21	6,56032	0,09024	98,0706	1,06941
22	5,05052	0,14917	110,006	0,67872
23	3,96038	0,19054	121,135	0,45128
24	3,25878	0,22451	127,795	0,33072
25	2,81932	0,25892	131,716	0,26285
26	2,54297	0,29569	135,028	0,21948
27	2,36801	0,33313	138,854	0,18772
28	2,22284	0,36646	143,594	0,15966
29	2,03988	0,39049	149,214	0,13177
30	1,85905	0,40511	155,494	0,1081
31	1,71937	0,41205	162,025	0,09132
32	1,6247	0,41255	168,563	0,08111
33	1,56631	0,40712	175,033	0,07642
34	1,53545	0,39604	-178,596	0,07632
35	1,52552	0,37979	-172,359	0,08002
36	1,53142	0,35902	-166,306	0,08677
37	1,54924	0,33456	-160,5	0,09581
38	1,57569	0,30737	-155,005	0,10639
39	1,60782	0,27848	-149,88	0,11785
40	1,64284	0,24888	-145,156	0,12959
41	1,67819	0,21937	-140,812	0,14122
42	1,7116	0,19047	-136,728	0,15251
43	1,74114	0,16223	-132,646	0,16346
44	1,76545	0,13415	-128,099	0,17427
45	1,78397	0,10522	-122,238	0,18527
46	1,79724	0,07424	-113,099	0,19683
47	1,80721	0,04114	-92,5806	0,20924
48	1,81762	0,02437	-10,8838	0,22252
49	1,8343	0,06206	44,5558	0,23634
50	1,86544	0,11635	63,03	0,24987
51	1,92153	0,17751	76,2539	0,26178
52	2,01499	0,24167	88,4567	0,27035
53	2,15929	0,30452	100,508	0,27372
54	2,36724	0,36174	112,539	0,27029
55	2,64858	0,41005	124,483	0,25935
56	3,00797	0,44777	136,255	0,24178
57	3,44398	0,47477	147,828	0,22089
58	3,94992	0,49192	159,247	0,20337

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4 - TestBench description

In this chapter we will describe with more details, the testing facilities and the instruments setup. We will also introduce accuracy and uncertainty. For the noise Temperature, where accurate results are harder to obtain, we will explain how these terms have been included in the measurement report in order to interpret correctly measurement results. The aim of this campaign, as anticipated, wasn't the extreme accuracy but the high volume of measurements in order to classify the working MMIC. Anyway, the definition of the accuracy is important for a correct measurement results understanding.

4.1 - 4-50 GHz S-parameter setup

This setup doesn't present any particular difficulties. SOLT is the calibration method which have been used, performed over two different frequency ranges: from 1 to 10 GHz, for the devices Table 2.2 a,b and from 20 to 50 GHz for the Table 2.2 c,d,e. The provided cal-kit was particularly damaged and the first set of data collected present an unacceptable ripple. Next tentative, more harmful for the cal-kit "health" conditions, worked better. Used equipment are listed in table 4.1.1 then the measurement setup conditions are reported in table 4.1.2.

	Model	SN
VNA	HP8510	
Probe In	GGB 67A GSG 200P	29982
Probe Out	GGB 67A GSG 200P	30701
Cable RF In	Gore	03977029
Cable RF Out	4FOBCOBXO34.03GW4O	03977028

Table 4.1.1 – 4 to 50 GHz S-parameter setup components

Calibration SOLT		
Frequency Range	1-10 GHz	20-50 GHz
N° of Points	51	51
Cal Power	10 dBm	10 dBm
Meas. Power	-5 dBm	-5 dBm
Attenuation P1	20 dB	20 dB
Attenuation P2	0 dB	0 dB
Power Slope	0.1 dB/GHz	0.1 dB/GHz

Table 4.1.2 – 4 to 50 GHz Setup settings

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4.2- 78-118 GHz S-parameter setup

This setup is a little more difficult than the previous one. In order to extend the VNA 8510 frequency range, external millimetric test-set extension has been used. To drive the internal components of this extension a secondary Frequency synthesizer is necessary. Because elements that compose the test set have active devices inside, the relationship between realised output power at B, C and D and the nominal Power A displayed on the 8510 is not a simple offset where

$$PWR_A = PWR_{B/C/D} + b \quad (4)$$

Rather the observed relationship is

$$PWR_A = m_1 \cdot PWR_{B/C/D} + m_2 \cdot freq + b \quad (5)$$

$$m_1 > 1 \quad m_2 > 1$$

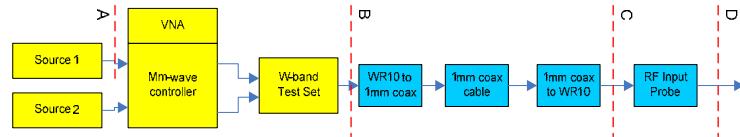


Fig 4.2.1 – RF input setup with WR10 mmWave extension

Linear regressions were estimated using measured data. The data consisted of measured power at C when source 1 nominal power ranged from -30 to -50 dBm. The usable “RF Level DUT IN” range is from -23 to -14 dBm. The measurement dynamic range is heavily compromised but this avoid test set components saturation or damaging. Calibration details are listed below. LNA measures are not in compression but not so far as we’d like. This choice seems to be the best compromise between calibration accuracy, measurement ripple and compression

	Model	SN
VNA	HP8510	
Millimeter Test set Extension		
Probe In	GGB 120 GSG 100 BT	
Probe Out	GGB 120 GSG 100 BT	
Cable RF In		
Cable RF Out		

Table 4.2.1 – 78 to 118 GHz S-parameter setup components

Calibration SOLT	
Frequency Range	70-118 GHz
N° of Points	101
Cal Power	-30 dBm
Meas. Power	-47 dBm
Attenuation P1	0 dB
Attenuation P2	0 dB
Power Slope	0 dB/GHz

Table 4.2.1 – 78 to 118 GHz Setup settings

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4.3 - 26-39 Noise Temperature setup

This setup have been used to characterise the MMIC of the table 2.2.c,d,e. It is represented in figure 4.3.1 and the components are listed in table 4.3.1. The frequency range move from 26 to 39 GHz. The NFM extension, built by C-TIP allows to test the noise up to 39 GHz. In order to increase the measurement accuracy we applied some useful tricks. We have to improve the noise source matching, and take into account the losses in the probes. The effective ENR must be translated (Fig 4.3.6), moving the NS reference plane on the RF input probetips, using the equation:

$$ENR(dB) = ENR_{NS}(dB) + G_{av_{PROBES}}(dB) + G_{av_{6DbPAD}}(dB) \quad (6)$$

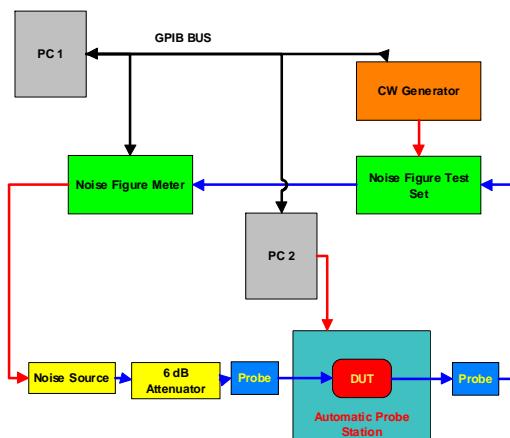


Figure 4.3.1 - Noise Measurement setup

	Model	SN
NFM	HP8970	
Noise Source	346C-K01	3328A04559
Attenuator	Wiltron 41V-6	960061
40 GHz NFM ext.		
Probe In	GGB 67A GSG 200P	29982
Probe Out	GGB 67A GSG 200P	30701
Cable RF Out		

Table 4.3.1 – 26 to 39 GHz Noise setup components

In order to correctly translate the Noise source reference plane, the available gain of the input RF probe and the 6dB precision attenuator should be calculated. We used the insertion loss instead of the available gain because the software to calculate the available gain weren't fixed. We will demonstrate that the introduced error is negligible where the matching if higher.

$$ENR(dB) = ENR_{NS}(dB) + S_{21_{PROBES}}(dB) + S_{21_{6DbPAD}}(dB) \quad (7)$$

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Probe available gain, based on the reflecting coefficients indicated in fig. 3.2.2, is calculated using the equation that follows

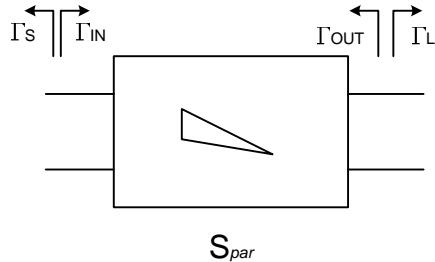


Fig 4.3.2 – Probe block and reflecting coefficient definition

$$G_{av}^{PROBE}(dB) = |S_{21}^{PROBE}|^2 \cdot \frac{1 - |\Gamma_s|^2}{|1 - \Gamma_s \cdot S_{11}^{PROBE}| \cdot (1 - |\Gamma_{OUT}|^2)} \quad (8)$$

$$\Gamma_{OUT} = S_{22}^{PROBE} + \frac{S_{21}^{PROBE} \cdot S_{12}^{PROBE} \cdot \Gamma_s}{1 - \Gamma_s \cdot S_{11}^{PROBE}}$$

during probe characterisation (probe input port connected to the VNA) as well as measurements (input port connected to a matched noise source) $\Gamma_s \equiv 0$, then $\Gamma_{OUT} = S_{22}^{PROBE}$ expression could be so simplified

$$G_{av}^{PROBE}(dB) = |S_{21}^{PROBE}|^2 \cdot \frac{1 - |\Gamma_s|^2}{|1 - \Gamma_s \cdot S_{11}^{PROBE}| \cdot (1 - |S_{22}^{PROBE}|^2)} \quad (9)$$

It is clear that probe S-parameters are necessary. These are indirectly calculated by solving an equation system based on the gamma in measurements when the probetips are connected to the calibration standards, OPEN, SHORT and LOAD

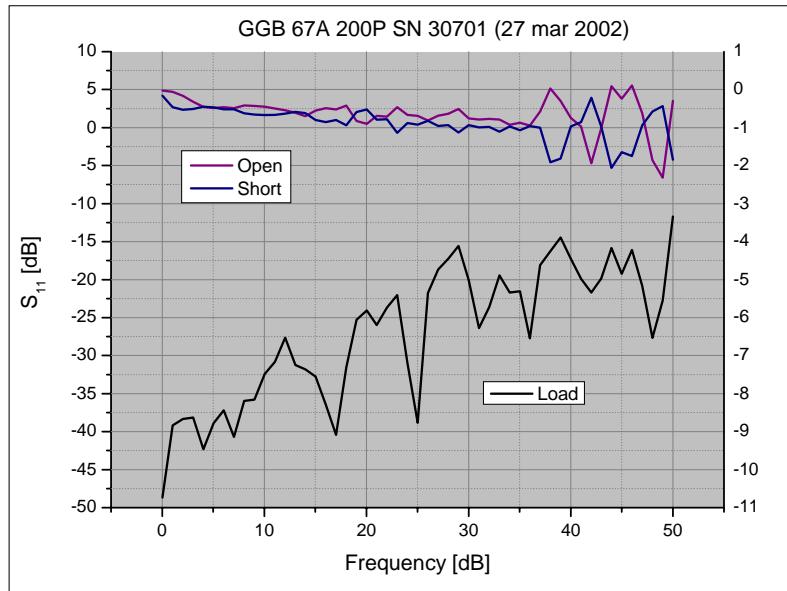
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$$\left\{ \begin{array}{l} \Gamma_{IN}^{OPEN} = S_{11_{PROBE}} + \frac{S_{21_{PROBE}} \cdot S_{12_{PROBE}} \cdot \Gamma_L^{OPEN}}{1 - \Gamma_L^{OPEN} \cdot S_{22_{SONDA}}} \\ \Gamma_{IN}^{SHORT} = S_{11_{PROBE}} + \frac{S_{21_{PROBE}} \cdot S_{12_{PROBE}} \cdot \Gamma_L^{SHORT}}{1 - \Gamma_L^{SHORT} \cdot S_{22_{PROBE}}} \\ \Gamma_{IN}^{LOAD} = S_{11_{PROBE}} + \frac{S_{21_{PROBE}} \cdot S_{12_{PROBE}} \cdot \Gamma_L^{LOAD}}{1 - \Gamma_L^{LOAD} \cdot S_{22_{PROBE}}} \end{array} \right. \quad (10)$$

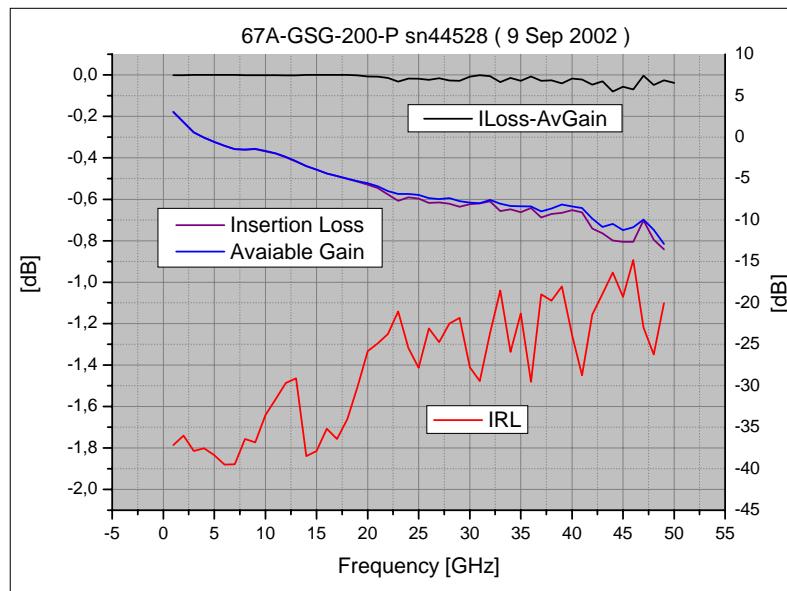
If properly inverted and the probe could be considered like a reciprocal network ($S_{21_{PROBE}} \cong S_{12_{PROBE}}$) we can define the available gain. The equation system is shown below

$$\left\{ \begin{array}{l} S_{11_{PROBE}} = \Gamma_{IN}^{LOAD} + \frac{S_{21_{PROBE}} \cdot S_{12_{PROBE}}}{1 - \Gamma_L^{OPEN}} \\ S_{22_{PROBE}} = \frac{\left(\frac{\Gamma_{IN}^{SHORT} - S_{11_{PROBE}}}{\Gamma_L^{SHORT}} - \frac{\Gamma_{IN}^{OPEN} - S_{11_{PROBE}}}{\Gamma_L^{OPEN}} \right)}{\Gamma_{IN}^{SHORT} - \Gamma_{IN}^{OPEN}} \\ S_{21_{PROBE}} \cdot S_{12_{PROBE}} = \frac{\Gamma_{IN}^{SHORT} - S_{11_{PROBE}}}{\Gamma_L^{SHORT}} + S_{22_{PROBE}} \cdot (S_{11_{PROBE}} - \Gamma_{IN}^{SHORT}) \end{array} \right. \quad (11)$$

We will get Γ_L^{OPEN} , Γ_L^{SHORT} , Γ_L^{LOAD} from the calibration kit datasheet and collect Γ_{IN}^{OPEN} , Γ_{IN}^{SHORT} , Γ_{IN}^{LOAD} from the S₁P probe measurements, reported in fig 4.3.3, with the VNA reference plane at the probe input (fig 4.3.3).

Fig 4.3.3 – Probe S_{1p} standard measurements

It is widely demonstrated, by the results reported in graphs (fig 4.3.4 for the probes, and fig 4.3.5 for the attenuator), that for a moderate accuracy measurement campaign, if the elements which compose the test setup are well matched, we can approximate the Available Gain with the Insertion Loss. Following the scheme in fig 4.3.6 the ENR table used for the measurements is listed in table 4.3.2, where the unadjusted ENR table, pad attenuator values and probe losses come from the manufacturer datasheets

Fig 4.3.4 – Input probe IL vs G_{AV} comparison

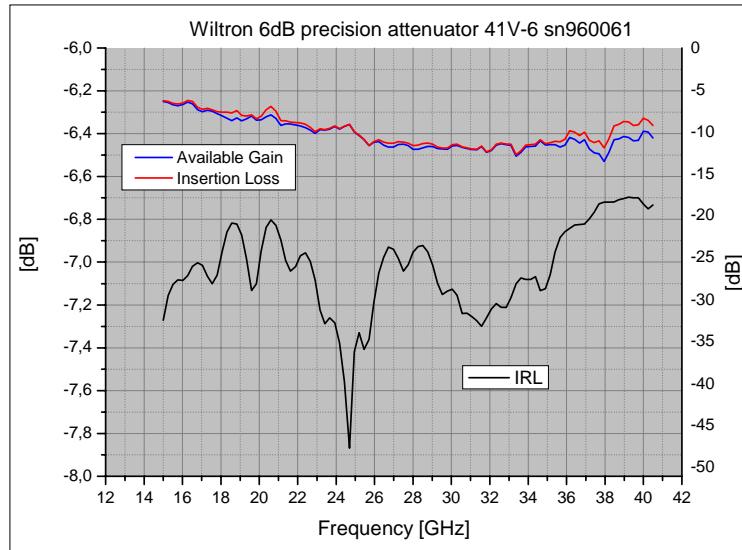
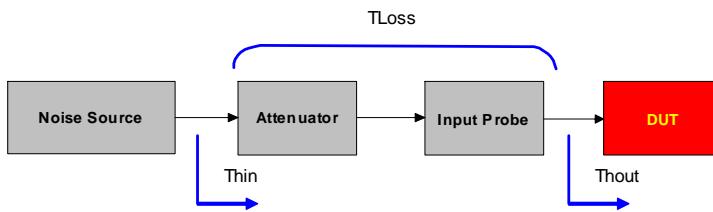
Fig 4.3.5 – 6dB attenuator Pad IL vs G_{AV} comparison

Fig 4.3.6 – ENR translation description

Frequency [GHz]	Unadjusted NS ENR [dB]	Precision Pad insertion loss [dB]	RF INPUT probe losses [dB]	Adjusted ENR [dB]
26	12,52	6,39	0,57	5,56
27	12,16	6,39	0,58	5,19
28	11,76	6,43	0,58	4,75
29	11,47	6,41	0,59	4,47
30	11,33	6,44	0,60	4,29
31	11,39	6,46	0,60	4,33
32	11,39	6,43	0,61	4,35
33	11,45	6,44	0,62	4,39
34	11,42	6,45	0,62	4,35
35	11,41	6,41	0,63	4,37
36	11,43	6,41	0,64	4,38
37	11,38	6,43	0,64	4,31
38	11,30	6,43	0,65	4,22
39	11,23	6,39	0,66	4,18
40	11,08	6,40	0,67	4,01

Table 4.3.2 – 26 to 40 GHz ENR translation

4.4 - 75-98 Noise temperature setup

In order to characterise the noise performances of the devices of table 2.2 f,g we have set up a W-band test bench (schematically described in Fig 4.4.1). Compared with the previous one it looks identical from the conceptual point of view. Major changes are the noise source, the receiver, which extend over the W-band the 8970 measurement capabilities and the 100 um pitch probes. These components are all WR10 waveguide flanged and optimized for this frequency range. The waveguide isolator is used to improve the noise source match as well as the precision attenuator used in the 26 to 39 setup. In order to match the 8970 dynamic range, to measure the 100LNA_01A, a 10dB attenuator pad has been connected between the receiver and the NFM. For the same reason, to measure the 86LNA_01A a 20dB attenuator pad has been used. Table 4.4.1 is a component list. Fig. 4.4.3 a,b are pictures of the setup.

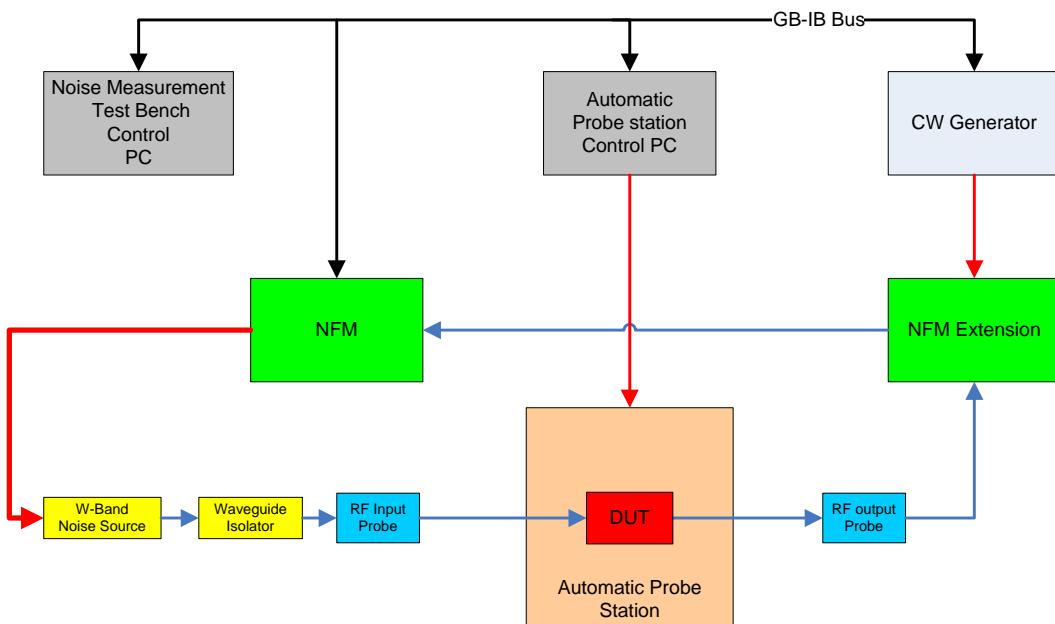


Fig. 4.4.1 – Wband Noise setup description

	Model	SN
NFM	HP8970	
Noise Source	Noise/COM NC5110 opt 5	K314
Isolator	Dorado FI-10	147
70-100 GHz NFM ext.	Millitech	
Probe In	GGB 120 GSG 100BT	15160
Probe Out	GGB 120 GSG 100BT	8402

Table 4.4.1 – 75 to 98 GHz Noise setup components

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Adopting the same principles developed in the previous paragraph, we will move the reference plane forward to the probetips as described in Fig. 4.4.2. The components value table 4.3.2 has been collected by the datasheets provided by the manufacturer. We have estimated a 0.2 dB losses for the waveguide bend between the isolator and the probe (fig. 4.4.3-a).

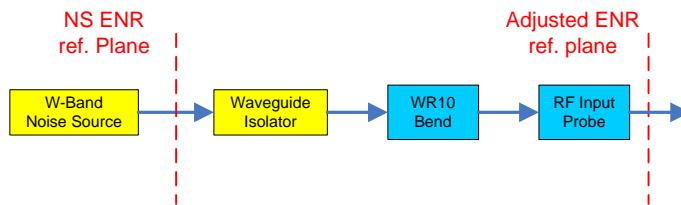


Fig 4.4.2 – Wband ENR translation

Frequency [GHz]	Unadjusted NS ENR [dB]	Pad insertion loss [dB]	RF INPUT probe losses [dB]	Bend Losses (estimated)	Adjusted ENR [dB]
75,00	17,70	1,95	0,56	0,20	14,99
76,00	17,73	1,95	0,60	0,20	14,98
77,00	18,93	1,88	0,62	0,20	16,23
78,00	18,68	1,80	0,63	0,20	16,05
79,00	18,62	1,73	0,63	0,20	16,06
80,00	19,10	1,66	0,63	0,20	16,61
81,00	18,44	1,64	0,62	0,20	15,98
82,00	18,20	1,60	0,60	0,20	15,80
83,00	17,82	1,54	0,58	0,20	15,50
84,00	17,62	1,46	0,56	0,20	15,40
85,00	17,15	1,40	0,54	0,20	15,01
86,00	16,25	1,36	0,52	0,20	14,17
87,00	15,68	1,30	0,50	0,20	13,68
88,00	15,60	1,25	0,47	0,20	13,68
89,00	15,05	1,22	0,45	0,20	13,18
90,00	15,40	1,25	0,44	0,20	13,51
91,00	14,43	1,30	0,42	0,20	12,51
92,00	14,43	1,34	0,41	0,20	12,48
93,00	14,20	1,34	0,40	0,20	12,26
94,00	13,50	1,35	0,39	0,20	11,56
95,00	13,74	1,34	0,39	0,20	11,81
96,00	12,90	1,34	0,39	0,20	10,97
97,00	13,22	1,36	0,39	0,20	11,27
98,00	12,41	1,35	0,39	0,20	10,47

Table 4.3.2 – 75 to 98 GHz ENR translation

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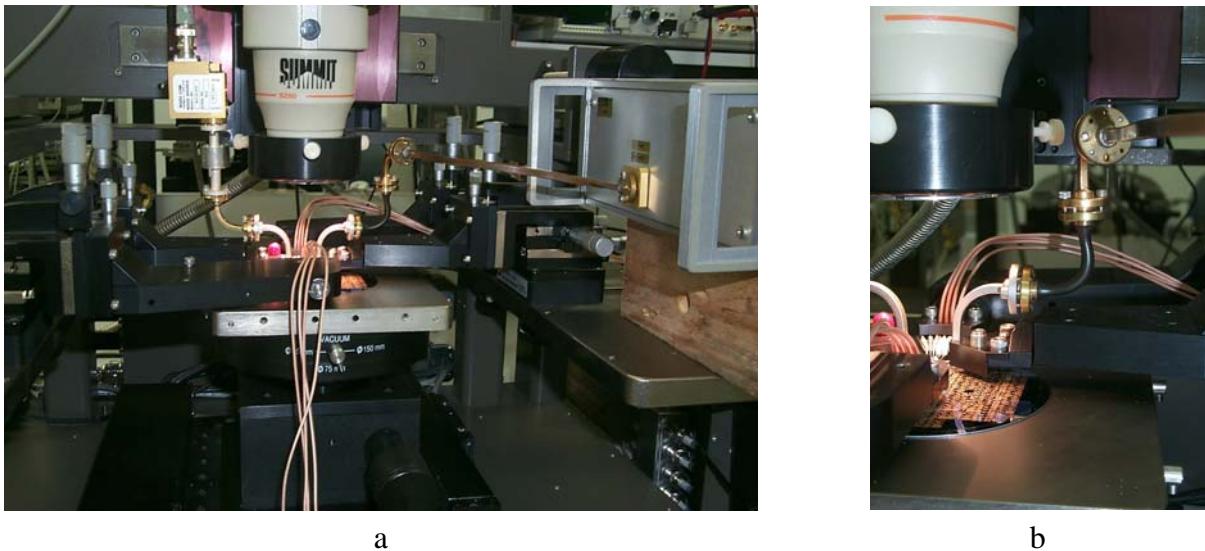


Fig. 4.4.3 – Wband noise setup

4.4 Uncertainty and accuracy

In order to provide more exhaustive noise measurements information and clarify the results, it is necessary to define an error bar. It should include all the terms which have influences on the absolute value. It takes into account the noise measurement system, which include the noise source, the DUT, the noise receiver and the system architecture. Duncan Boyd suggested a quite flexible uncertainty model. All the aspects related to the accuracy aren't explicitly considered by this model and have been briefly discussed in the previous paragraphs. This model associate a measurement uncertainty to a particular NF value based on the knowledge of VSWR's of the elements which composes the measurement system. Model accuracy is related to a reasonable DUT reverse isolation.

After the system calibration we record some data:

- F1 : DUT Noise factor
- G1 : DUT gain
- F2 : Uncorrected test receiver Noise factor

The general equation for the noise figure of two cascaded stages is:

$$F_{12} = F_1 + \frac{F_2 - 1}{G_1} \quad (12)$$

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Because we are interested to estimate DUT NF uncertainty, F1, it will be rearranged

$$F_1 = F_{12} - \frac{F_2 - 1}{G_1} \quad (13)$$

Applying Taylor theorem to the previous equation we can find the F1 uncertainty

$$\delta F_1 = \frac{\partial F_1}{\partial F_{12}} \cdot \delta F_{12} + \frac{\partial F_1}{\partial F_2} \cdot \delta F_2 + \frac{\partial F_1}{\partial G_1} \cdot \delta G_1 \quad (14)$$

the coefficient will be solved and results are

$$\begin{cases} \frac{\partial F_1}{\partial F_{12}} = 1 \\ \frac{\partial F_1}{\partial F_2} = -\frac{1}{G_1} \\ \frac{\partial F_1}{\partial G_1} = \frac{F_2 - 1}{G_1^2} \end{cases} \quad (15)$$

so that

$$\delta F_1 = \delta F_{12} - \frac{1}{G_1} \cdot \delta F_2 + \frac{F_2 - 1}{G_1^2} \cdot \delta G_1 \quad (16)$$

because generally units is logarithmic decibel, or dB the expression become

$$\delta NF_1 = \frac{F_{12}}{F_1} \delta NF_{12} - \frac{F_2}{F_1 \cdot G_1} \cdot \delta NF_2 + \frac{F_2 - 1}{F_1 \cdot G_1} \cdot \delta G_1 (dB) \quad (17)$$

ENR uncertainty doesn't explicitly appear in the equation but it is clear that there is an uncertainty associated with the ENR and this will contribute to the overall uncertainty

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The δENR only influences the first two terms in the previous equation

$$\left(\frac{F_{12}}{F_1} - \frac{F_2}{F_1 \cdot G_1} \right) \cdot \delta\text{ENR} \quad (18)$$

Since the causes of the uncertainties in the four δ factors are different, the terms can be combined in a root-sum-of-squares (RSS) fashion, which provides a realistic overall uncertainty value. The equation for the overall NF uncertainty is therefore:

$$\delta\text{NF} = \left\{ \left[\left(\frac{F_{12}}{F_1} \right) \cdot \delta\text{NF}_{12} \right]^2 + \left[\frac{F_2}{F_1 \cdot G_1} \cdot \delta\text{NF}_2 \right]^2 + \left[\frac{F_2 - 1}{F_1 \cdot G_1} \cdot \delta G_1(\text{dB}) \right]^2 + \left[\left(\frac{F_{12}}{F_1} - \frac{F_2}{F_1 \cdot G_1} \right) \cdot \delta\text{ENR} \right]^2 \right\}^{0.5} \quad (19)$$

One of the most significant parameters affecting the uncertainties in is δENR , the uncertainty of the noise source. For best uncertainty when measuring low-noise devices, low ENR sources should be used. This results in a lower $\delta\text{InstrumentNF}$ since the low ENR exercises less of the measurement detector's dynamic range. There is a further advantage for using a low-ENR source in that its impedance is more constant between the on and off states. This is because a low ENR source (with ENR of typically 5 dB) is basically a high-ENR source (with ENR of typically 15 dB) with an additional attenuator. Our measurement system wasn't provided of a low-ENR noise source. In order to reduce the ENR value down to match the detector dynamic range and improve the isolation a 6dB attenuator pad has been used in a 26 to 39 GHz system. then a waveguide isolator has been used in the 75 to 98 GHz. The suggested model doesn't take into account attenuator/isolator and input probe uncertainty. We consider the insertion losses of these components and move forward the reference plane to the probetips. this operation increase the ENR uncertainty but measurements are more accurate. As demonstrate in the previous paragraph, if chain components are very well isolated, error introduced by using the insertion loss instead of the available gain are negligible. More relevant is the uncertainty introduced by the attenuator/isolator and input probe, because they aren't considered in the model and just only estimated within ENR uncertainty. Hence the overall estimated NF uncertainty is a best case. Real condition would require wider error bars. Estimated Uncertainty spreadsheet are listed in table 4.5.1-5

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From tables 4.5.2-6 we calculate the percentage relative uncertainty showed in table 4.5.1. It is clear the relevance of this factor when we consider ultra low noise devices. Uncertainty weight decrease while the frequency raise. Even if an high uncertainty value can be unacceptable at room temperature, it become a paradox at cryogenic temperature, because in first approximation, uncertainty is a temperature invariant.

$\frac{U(Te)}{Te} \cdot 100$				
32LNA_01A	32LNA_02A	43LNA_01A	86LNA_01A	100LNA_01A
42 %	44 %	31 %	23 %	19 %
42 %	42 %	32 %	23 %	18 %
34 %	34 %	29 %	22 %	20 %
34 %	34 %	34 %	24 %	19 %
32 %	32 %	35 %	25 %	19 %
32 %	32 %	36 %	20 %	20 %
31 %	31 %	32 %	24 %	16 %
30 %	30 %		24 %	19 %
30 %	30 %		23 %	15 %
28 %	29 %		23 %	17 %
32 %	33 %		21 %	15 %
33 %	34 %		26 %	17 %
34 %	35 %		26 %	16 %
30 %	30 %		28 %	18 %
			33 %	18 %
			25 %	

Table 4.5.1 – Percentage Relative Uncertainty

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5 - Measurement results

5.1 Description

Measurements that will be shown this chapter are S-parameter, in dB units, and noise temperature, in Kelvin degree units. The first and the second graph of each design show the simulations compared with the “all working” MMICs behaviour. Devices have been grouped by design and wafer serial number. Responses of MMIC which lies on the same wafer are drawn on the same colour. In order to have an high accuracy characterisation to compare with the simulations, for some devices, an higher number of points have been stored. Moreover, Gain and IRL with bias far from the design condition have been collected and shown in a graph. Bias details are listed in the table below the related graph. Cross reference with noise test with the same bias condition will be coming soon . In order to get more information regarding the devices, some analysis have been conducted on the collected data. We represent the distribution of the average gain and Te over 100% BW. The pie graph of figure 5.1.1 represent the devices distribution of the CSR18 portion of IRA. We have measured only the LNA’s. STF are Stage test Fixture, which will be used for reverse engineering activity, HCA are discrete device which could be useful in order to create a cryogenic model and the TRL cal kit will be used to calibrate the instruments for modelling the devices.

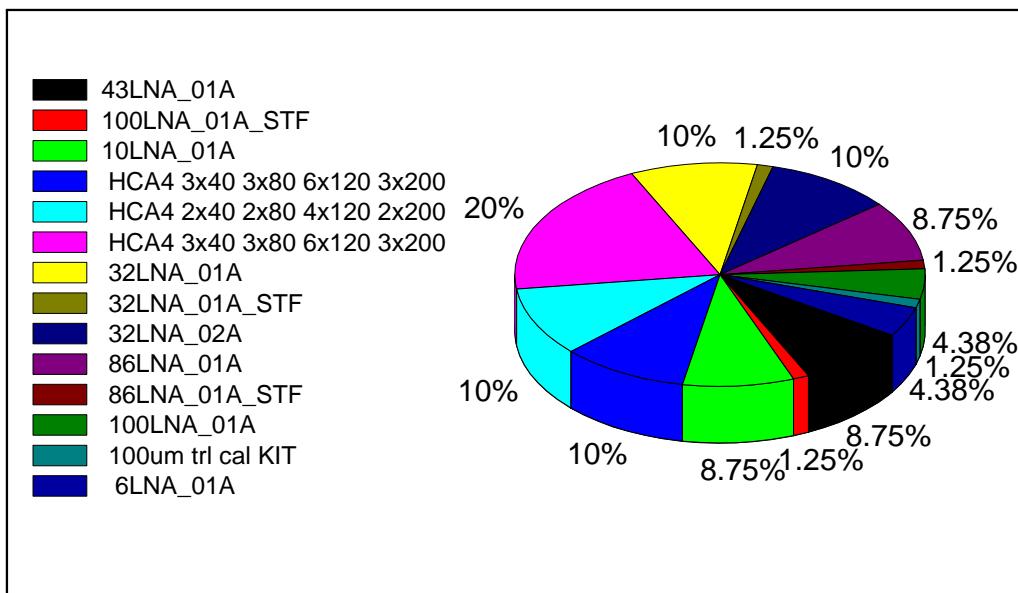


Fig. 5.1.1 – IRA device sharing percentage

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5.2 – 6LNA_01A

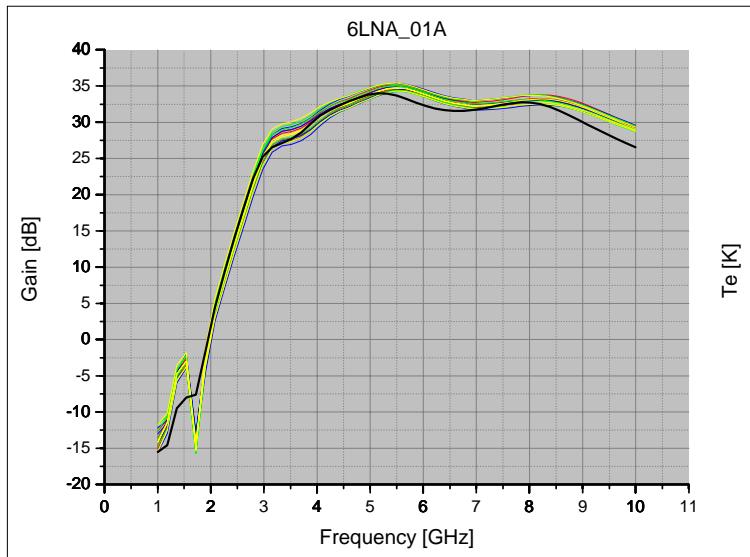


Fig 5.2.1 – 6LNA_01A Gain

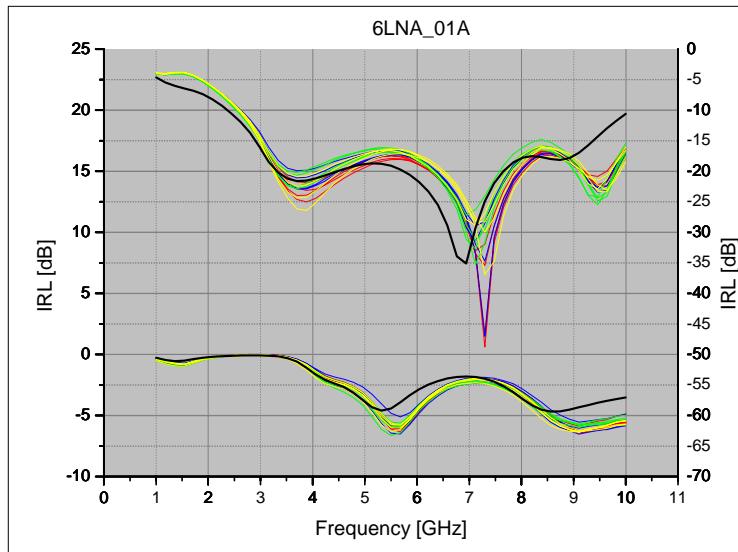


Fig 5.2.2 – 6LNA_01A IRL & ORL

- | | |
|---|--|
| ■ 4245-013 | ■ 4245-016 |
| ■ 4245-018 | ■ 4245-019 |

This LNA have been designed following the specification imposed by the PHAROS receiver constraints. PHAROS is a focal plane array receiver funded by RADIONET, which is a Network of excellence supported within FP6. This device had been carried out by a collaboration between the Microwave group of Tor Vergata University in Rome and IRA. Tor Vergata hadn't access to the NGC library models and the Foundry Rules. Device implementation had been followed by IRA.

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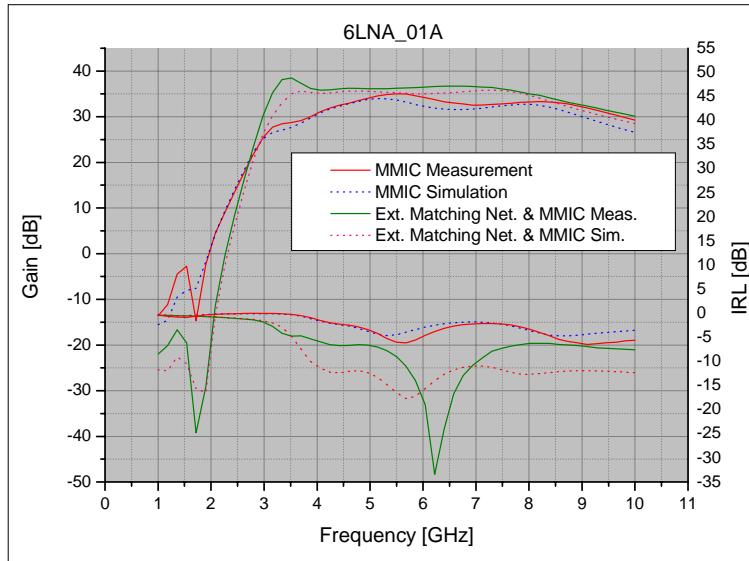


Fig 5.2.3 – 6LNA_01A IRL & Gain including simulated off chip network

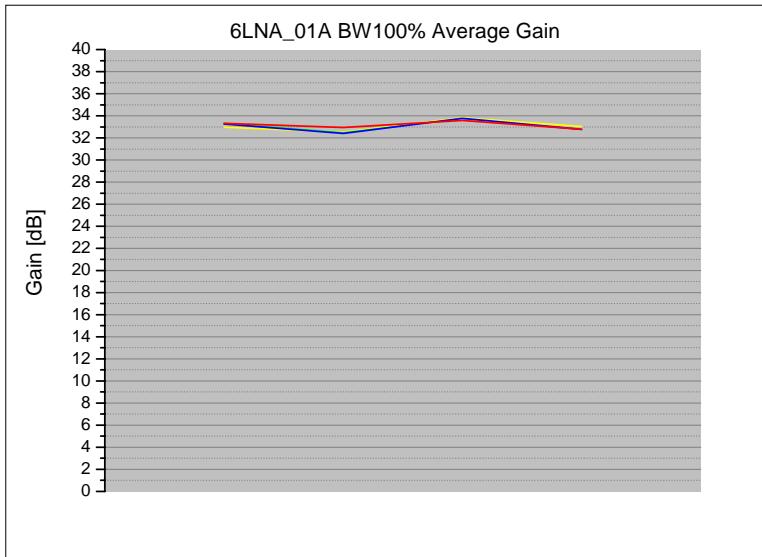


Fig 5.2.3 – 6LNA_01A BW100% Average Gain

Because this LNA has an off-chip matching network, MMIC-only simulation and measurements are compared in fig 5.2.1-2. The result of the combined response of MMIC measure with input matching network are shown Fig. 5.2.3. The external matching network gives a useful degree of freedom. It allows to specialise the LNA with a fractional bandwidth up to 110% or, with a more selective network, to obtain narrow bandwidth. In order to optimise the overall noise response and adapt the amplifier gain response to the IRA receiver specifications, we are planning to implement HTS filter in a input matching network. Filter and LNA have to provide gain between 4.3-5.8 GHz and 5.7-7.7 GHz.

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5.3 - 10LNA_01A

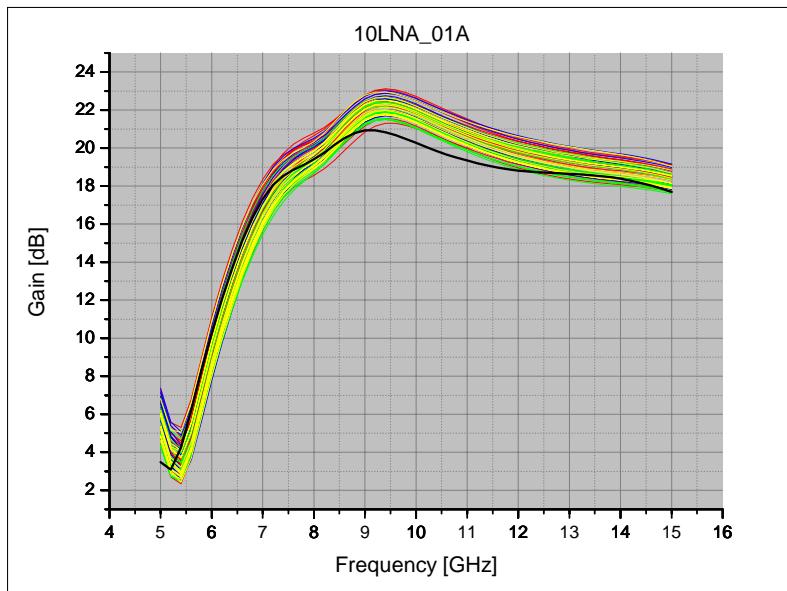


Fig 5.3.1 – 10LNA_01A Gain

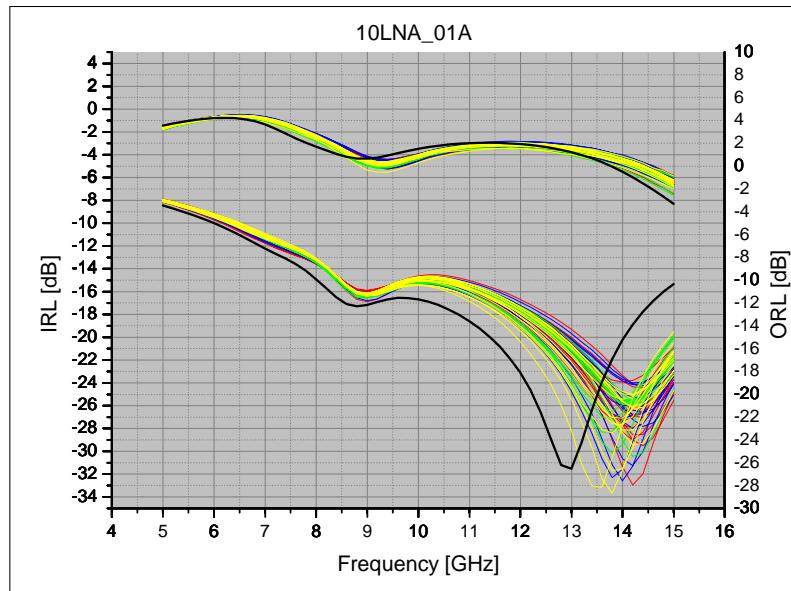


Fig 5.3.2 – 10LNA_01A IRL & ORL

■ 4245-013	■ 4245-016
■ 4245-018	■ 4245-019

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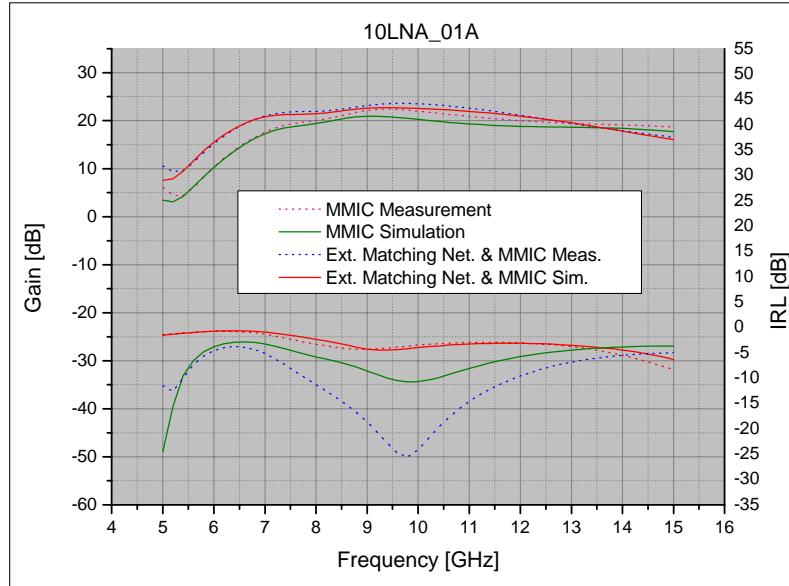


Fig 5.3.3 – 6LNA_01A IRL & Gain including simulated off chip network

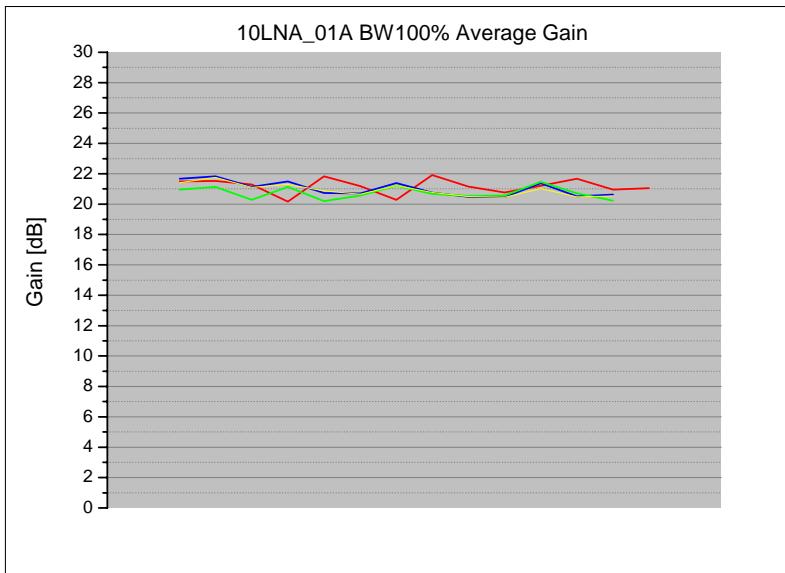


Fig 5.3.4 – 10LNA_01A BW100% Average Gain

The same consideration exposed for the previous device can be applied to this LNA. It has been designed in order to be installed in holography measurement system. This kind of equipment are used in radioastronomy to define with accuracy shape deformation of the parabolic dish. Also in this case the input matching network is off-chip. Specified working bandwidth lie between 8 to 12 GHz with a BW% of 49%. Accepting a poor IRL on the bandwidth edges, it can operate between 7,5 to 15 GHz extending the BW% up to 71%.

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5.4 – 32LNA_01A

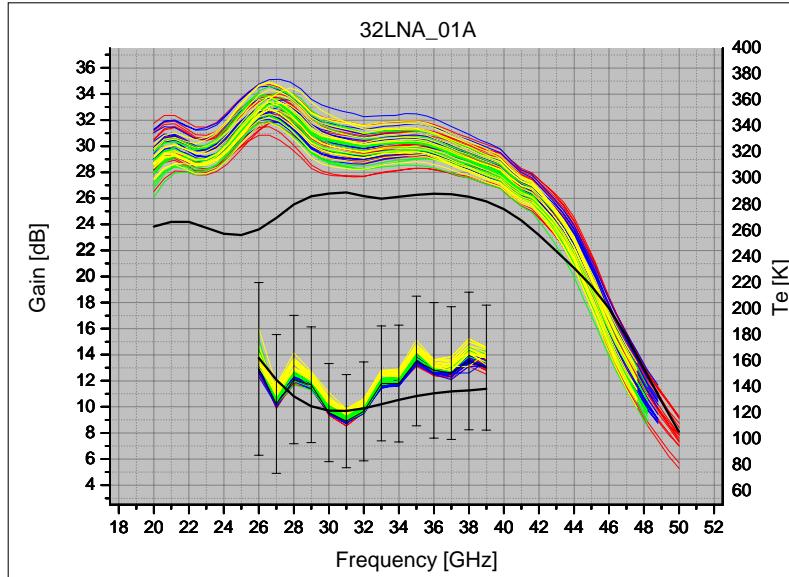


Fig 5.4.1 – 32LNA_01A Gain & Te

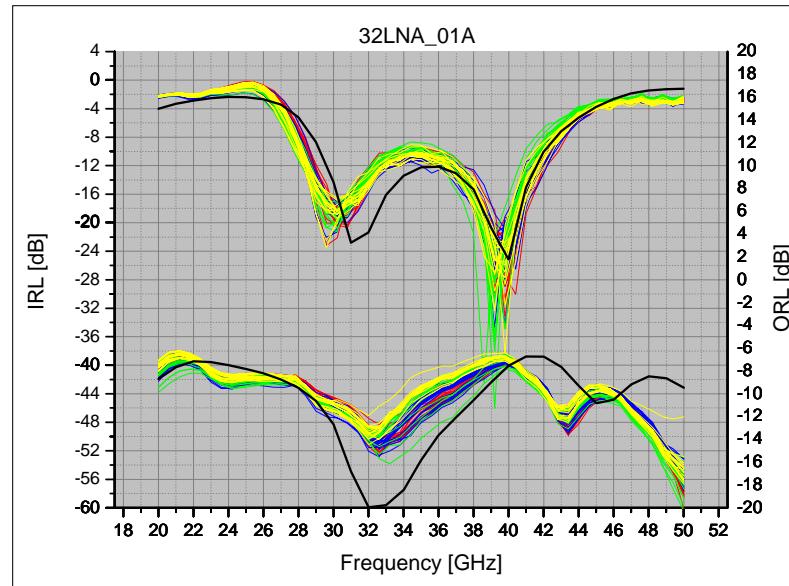


Fig 5.4.2 – 32LNA_01A IRL & ORL

- | | |
|------------|------------|
| ■ 4245-013 | ■ 4245-016 |
| ■ 4245-018 | ■ 4245-019 |

The noise temperature response of this design, according the estimated accuracy, match the specification. Gain in the working bandwidth is 6dB higher than the simulation, with an unwanted gain excess at the lower limit of BW, near 26 GHz.

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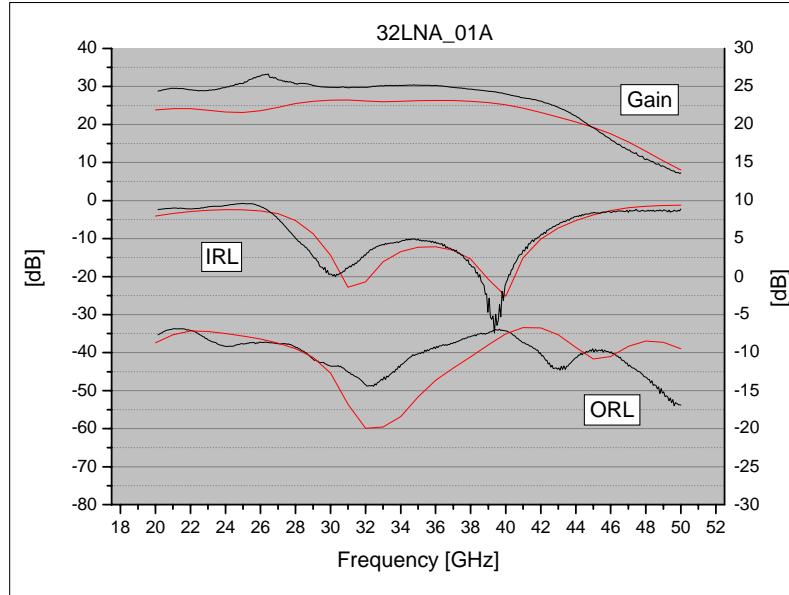


Fig 5.4.3 – 32LNA_01A Hi Resolution Gain & IRL & ORL

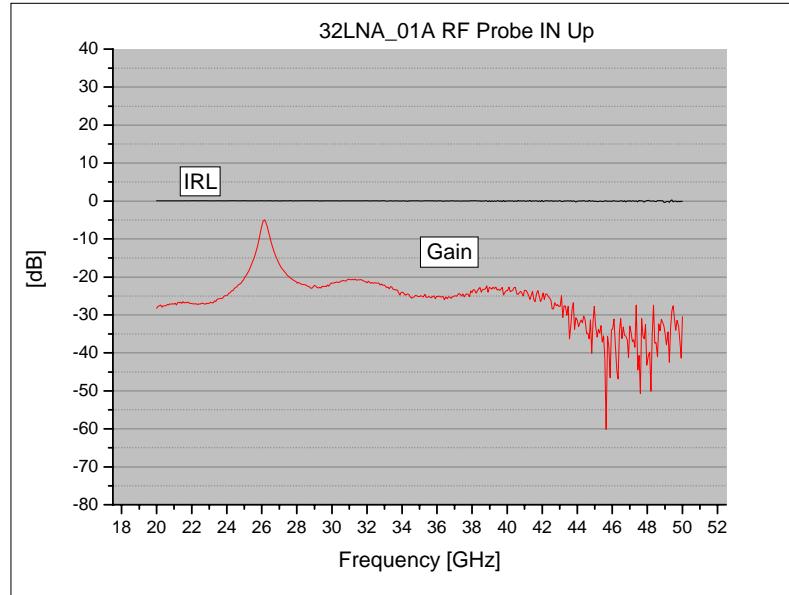


Fig 5.4.4 – 32LNA_01A IRL & Gain With RF in Raised Up

Considering fig. 5.4.4. the gain response has been collected with the rf input probe raised up. It is clear around 26 GHz a “gain peak” without RF input. For this design autooscillations will be deeply investigated. Evaluating the ORL differences between meas. and simulation in fig 5.4.3 the “anomalous” behaviour could be closer to the RF output than the RF input. EM simulations of part of MMIC circuit we will define which more accuracy the reasons of those differences.

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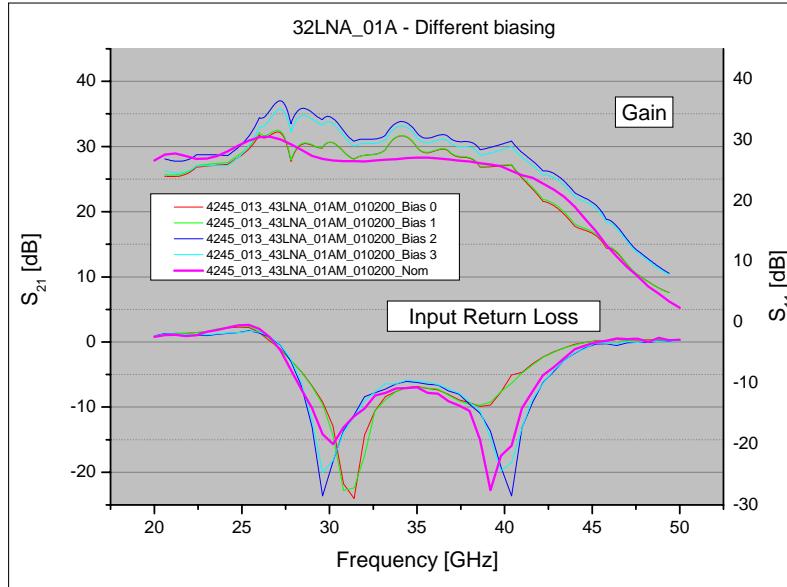


Fig 5.4.5 – 32LNA_01A IRL & Gain with several different biasing conditions

Measurement Name	D1 Vd [V]	Id [mA]	D2 Vd [V]	Id mA	D3 Vd [V]	Id mA	D4 Vd [V]	Id mA
CSR18_32LNA_01A_Nom	1,2	12	1,32	12	1,44	18	1,44	18
CSR18_32LNA_01A_Bias 0	0,5	5	1,32	5	1,44	8	1,44	11
CSR18_32LNA_01A_Bias 1	0,5	5	1,1	5	1,44	8	1,44	11
CSR18_32LNA_01A_Bias 2	1,2	5	1,32	5	1,44	18	1,44	18
CSR18_32LNA_01A_Bias 3	1,2	5	1,32	5	1,44	8	1,44	18

Table 5.4.1 – 32LNA_01A biasing

Measurements with bias condition set different to the design specifications show which is possible reducing sensibly the power consumption while having enough gain. In order to define the “BEST BIAS”, this data must be joined with the related noise response.

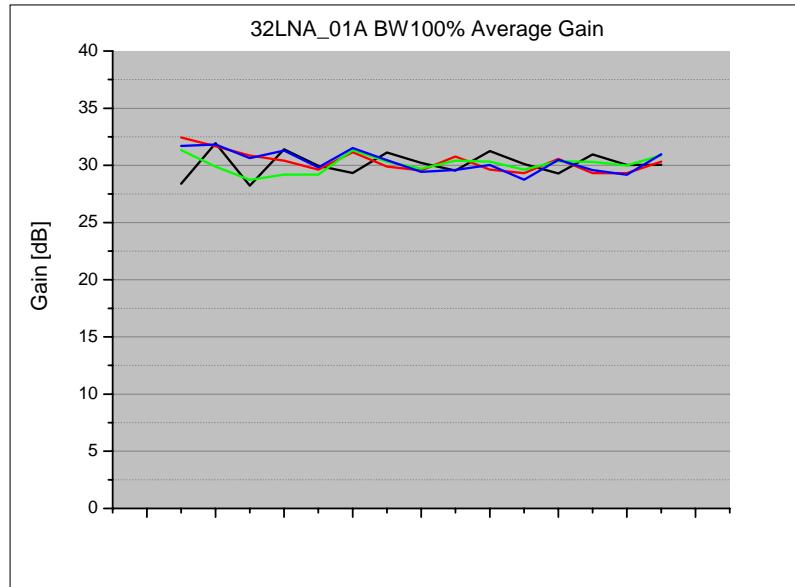


Fig 5.4.6 – 32LNA_01A BW100% Average Gain

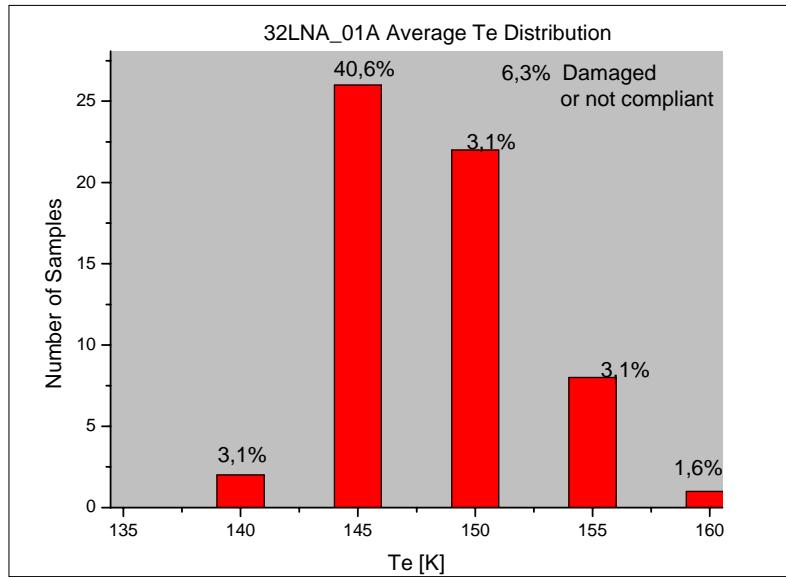


Fig 5.4.7 – 132NA_01A Average Te distribution

Figure 5.4.6 shows the average gain of each device in the frequency range between 26 to 40 GHz. The typical value is 30 dB. Figure 5.4.7 gives a distribution of the average Te, in the working bandwidth of this device, on the wafer-run

5.5– 32LNA_02A

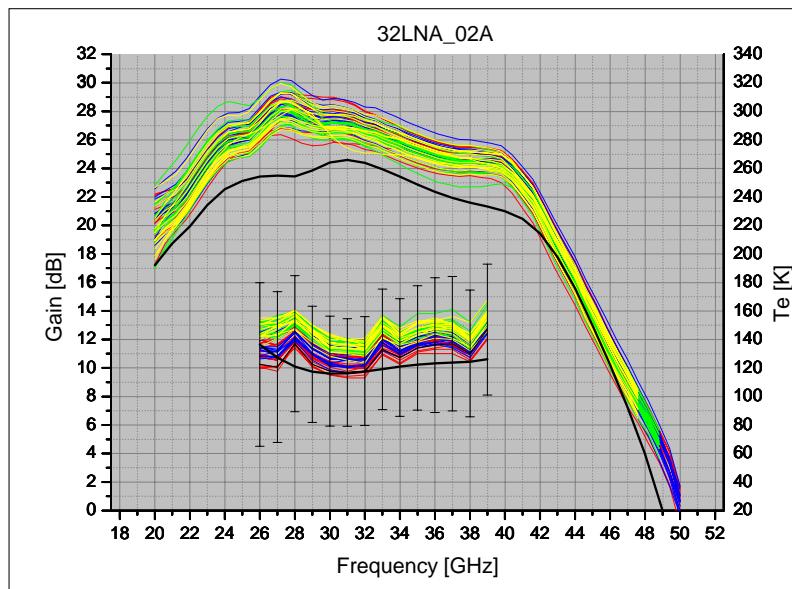


Fig 5.5.1 – 32LNA_02A Gain & Te

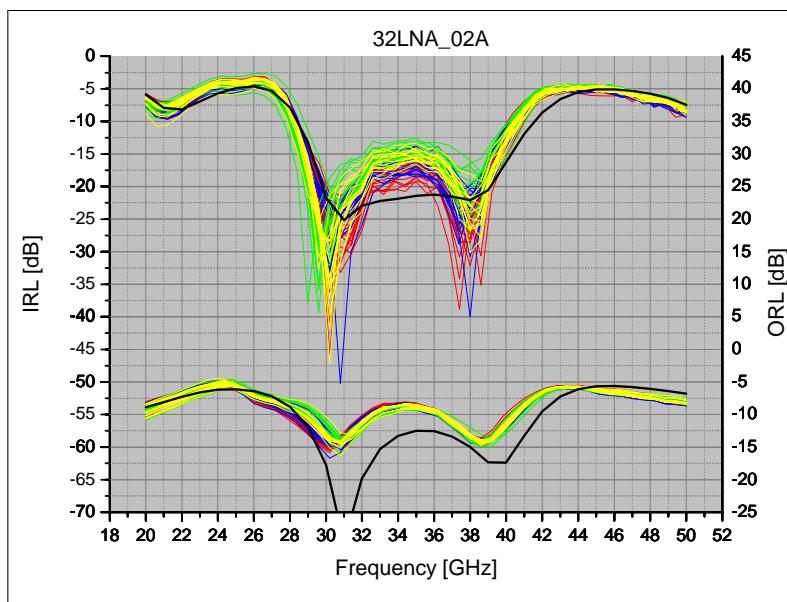


Fig 5.5.2 – 32LNA_02A IRL & ORL

- 4245-013
- 4245-016
- 4245-018
- 4245-019

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The LNA has a gain which is, on average, 3dB higher than the simulations. This depends by a NGC foundry process maturation which involve the entire wafer-run. They probably provide a more accurate gain alignment. Devices have lower losses and consequently higher gain. These results come after the library publications. The first two wafer of CSR18 run named 4245-013 and 4245-016 provide, as shown in fig 5.5.1, lower noise and gain higher than the other wafers.

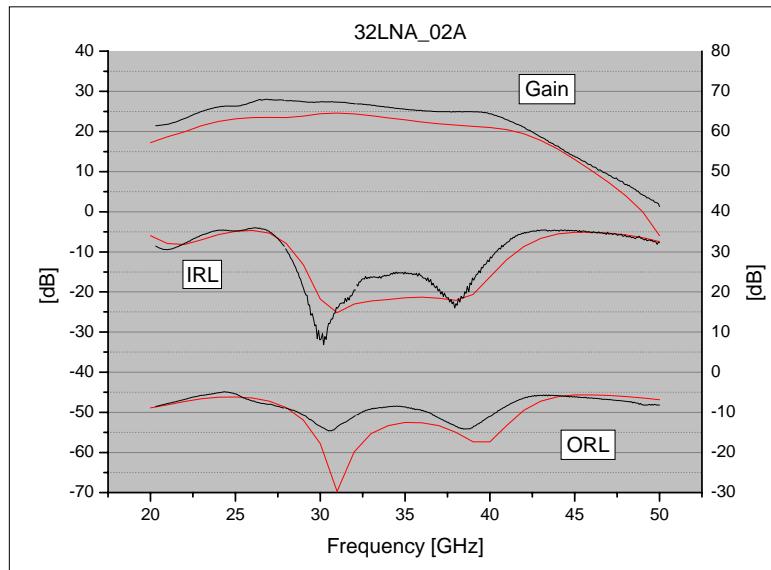


Fig 5.5.3 – 32LNA_02A Hi Resolution Gain & IRL & ORL

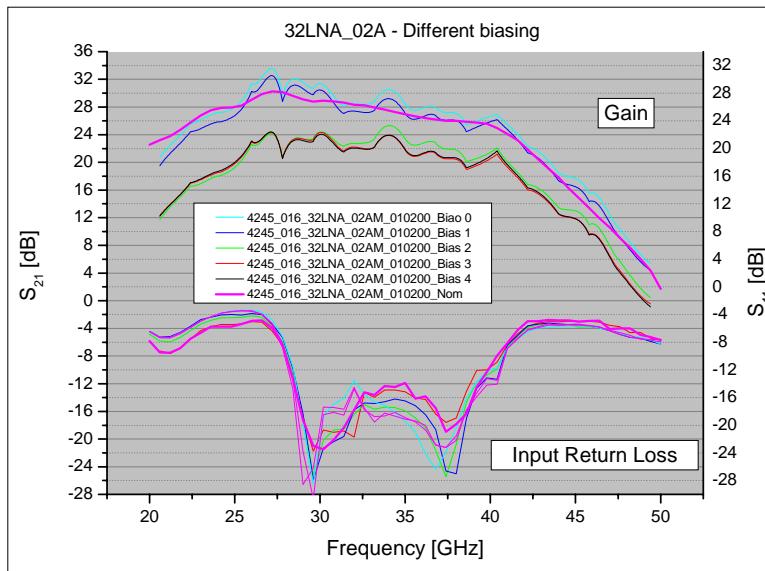


Fig 5.5.4 – 32LNA_02A IRL & Gain with several different biasing conditions

5.6– 43LNA_01A

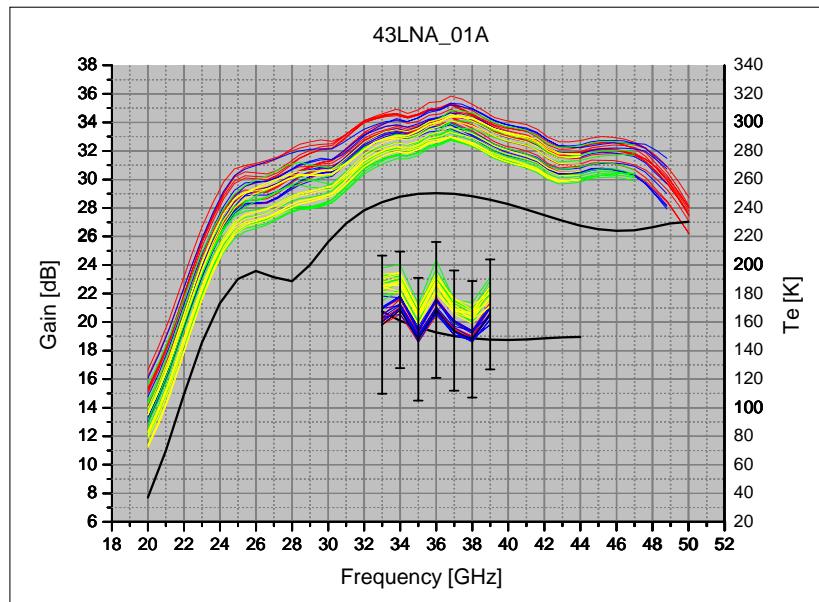


Fig 5.6.1 – 43LNA_01A Gain & Te

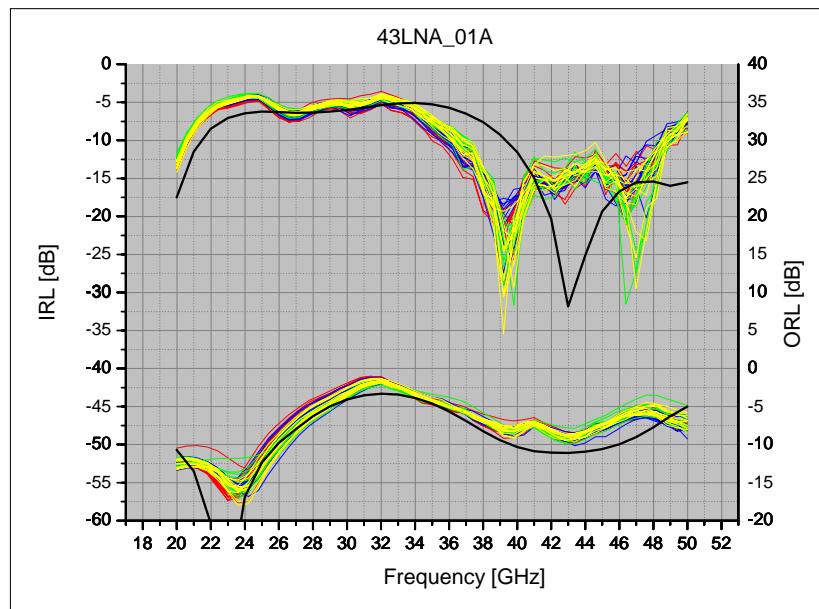


Fig 5.6.2 – 43LNA_01A IRL & ORL

■ 4245-013
■ 4245-018

■ 4245-016
■ 4245-019

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Also this LNA provide higher gain than expected. In order to define a “rule of thumb” we can assert that foundry process improvements allows extra gain of 1,2-1,5 dB per stage compared to the library. It depends also by the operating frequency. From the fig.5.6.5-6 we observe that the typical gain value is around 31.5 dB.

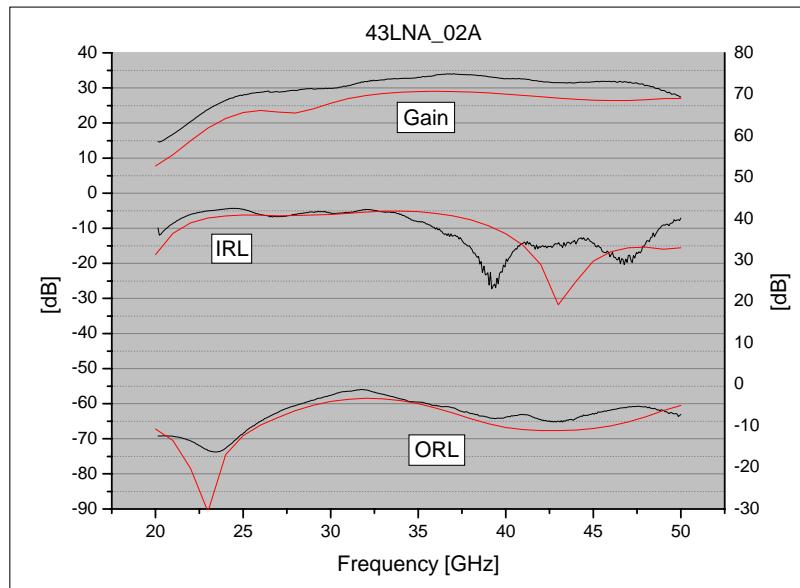


Fig 5.6.3 – 43LNA_01A Hi Resolution Gain & IRL & ORL

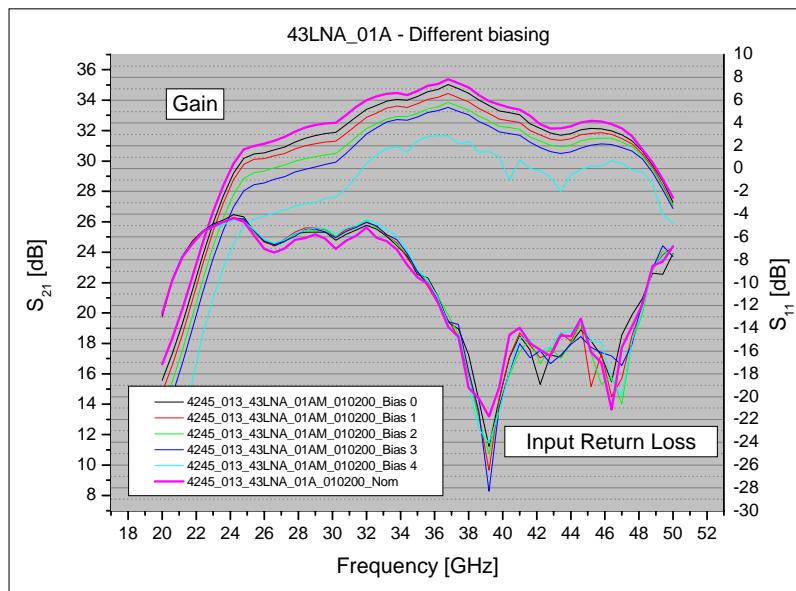
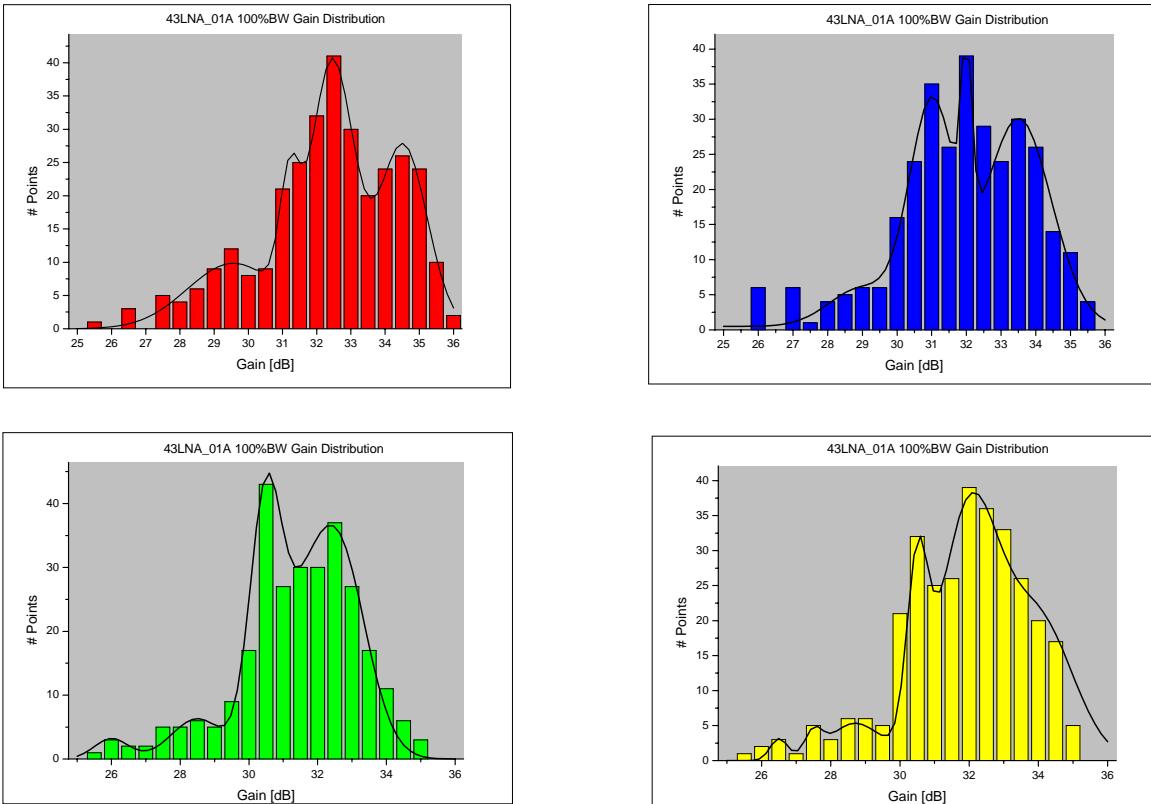


Fig 5.6.4 – 43LNA_01A IRL & Gain with several different biasing conditions

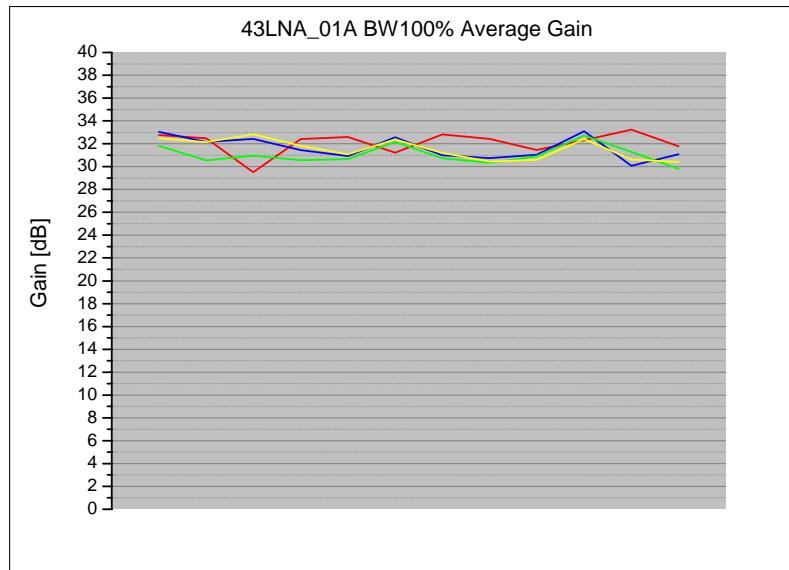
Measurement Name	D1	D2	D3	D4
	Vd [V]	Id [mA]	Vd [V]	Id mA
CSR18_43LNA_01A_Nom	1,08	12	1,08	12
CSR18_43LNA_01A_Bias 0	1,08	8	1,08	12
CSR18_43LNA_01A_Bias 1	1,08	8	1,08	8
CSR18_43LNA_01A_Bias 2	1,08	8	1,08	8
CSR18_43LNA_01A_Bias 3	1,08	8	1,08	8
CSR18_43LNA_01A_Bias 4	1,08	8	1,08	6

Table 5.6.1 – 43LNA_01A biasing

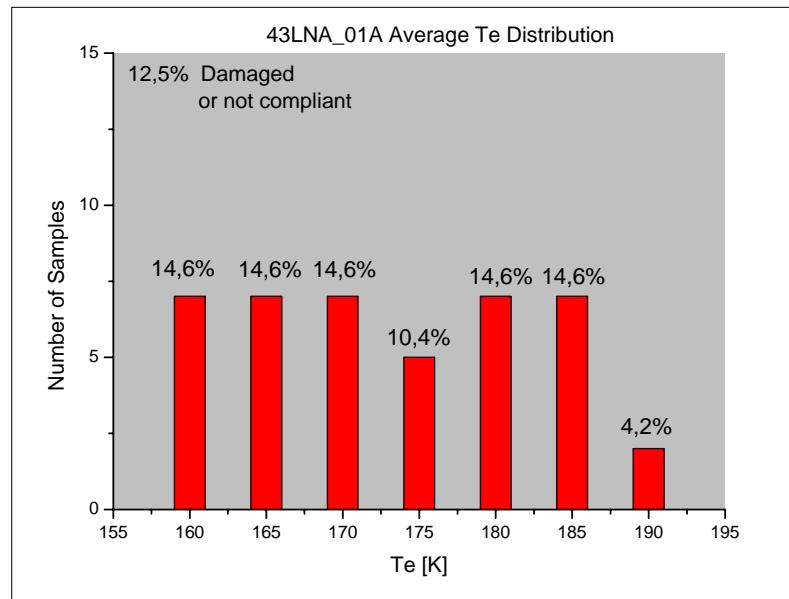
Gain response looks similar to the simulation but some flexes must be investigated. IRL is better than expected. It appears frequency shifted providing a match better than 15 dB over 50% BW. The upper part of BW has poor IRL which we try to improve when we design the waveguide input probe. ORL appear more similar to the simulation and this will focus the designer attention on the first two stages, during a reverse engineering activity, in order to discover discrepancy reasons.



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Fig 5.6.5 – 43LNA_01A Gain distribution**Fig 5.6.6 – 43LNA_01A BW100% Average Gain**

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**Fig 5.6.7 – 43LNA_01A Average Te distribution**

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5.7– 86LNA_01A

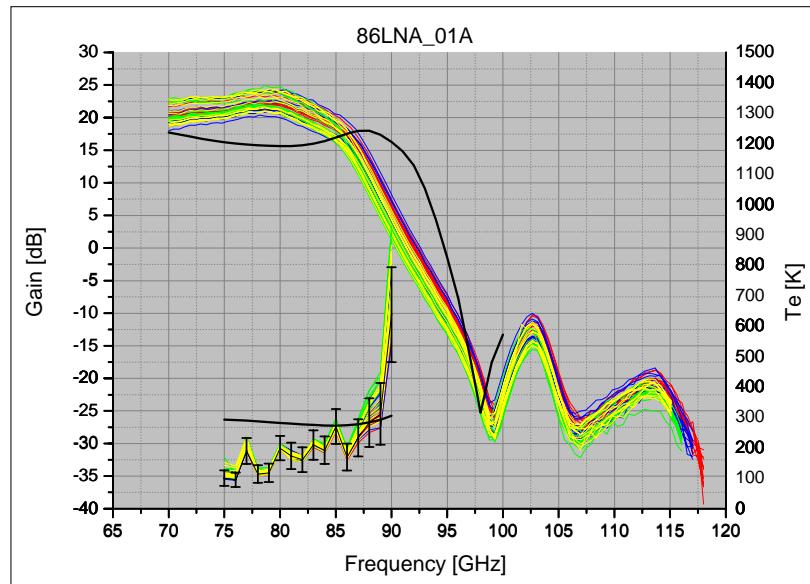


Fig 5.7.1 – 86LNA_01A Gain & Te

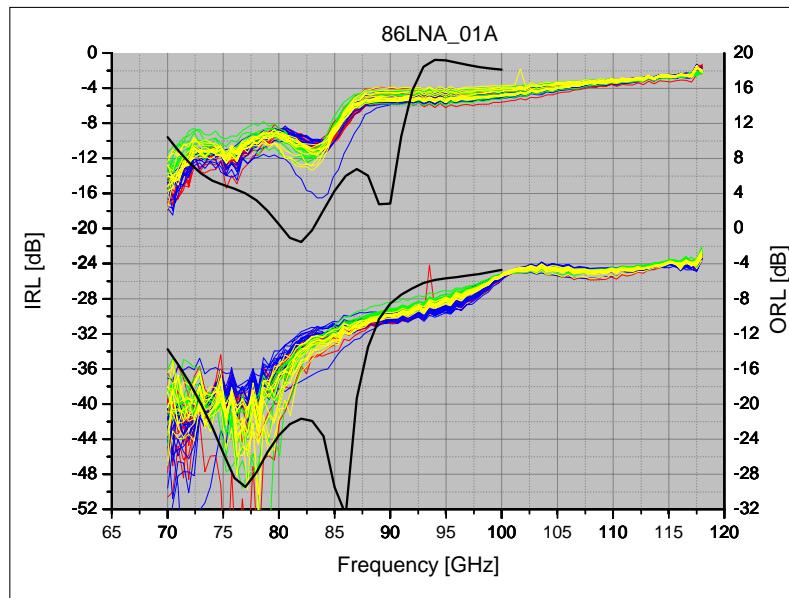


Fig 5.7.2 – 86LNA_01A IRL & ORL

■ 4245-013	■ 4245-016
■ 4245-018	■ 4245-019

If we observe the LNA response, it appears to be clearly narrower than expected from the simulation. Fractional bandwidth is about 19%. Gain flatness is about 3dB between 70 to 85 GHz, with a typical gain value of 21dB (Fig. 5.7.4). It could rise up to 25 at 20K. We haven't any information regarding Gain and Noise frequency response below 70 GHz, because WR-10 measurement test set were frequency limited. We could measure the device in Tor Vergata up to 50 GHz, but we haven't facilities which allow us to test these devices between 50 to 70 GHz. If necessary could be possible extend the frequency range of this device using 2 cascaded LNA's followed by an equaliser in order to obtain 21db Gain flat from 70 to 88 GHz, extending the bandwidth up to 23%.

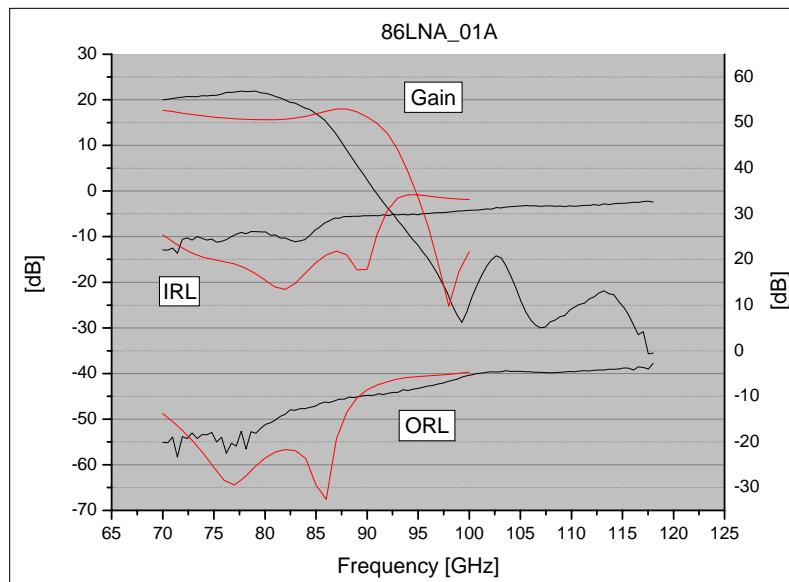
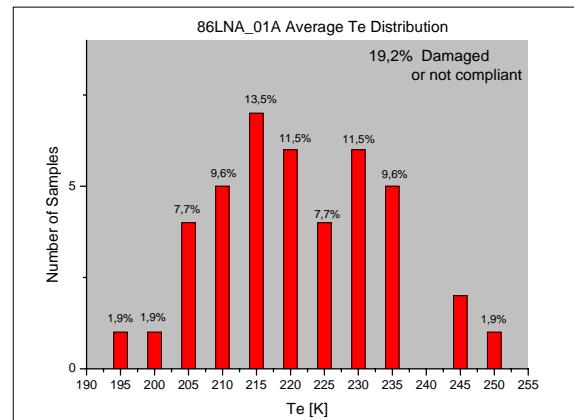
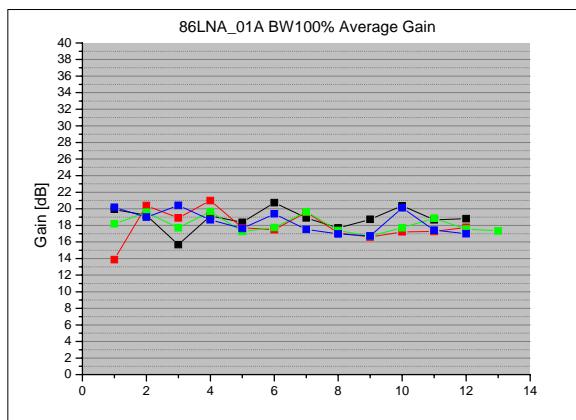


Fig 5.7.4 – 86LNA_01A Hi Resolution Gain & IRL & ORL



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Fig 5.7.4 – 86LNA_01A BW100% Average Gain

Fig 5.7.5 – 86LNA_01A Average Te distribution

5.8– 100LNA_01A

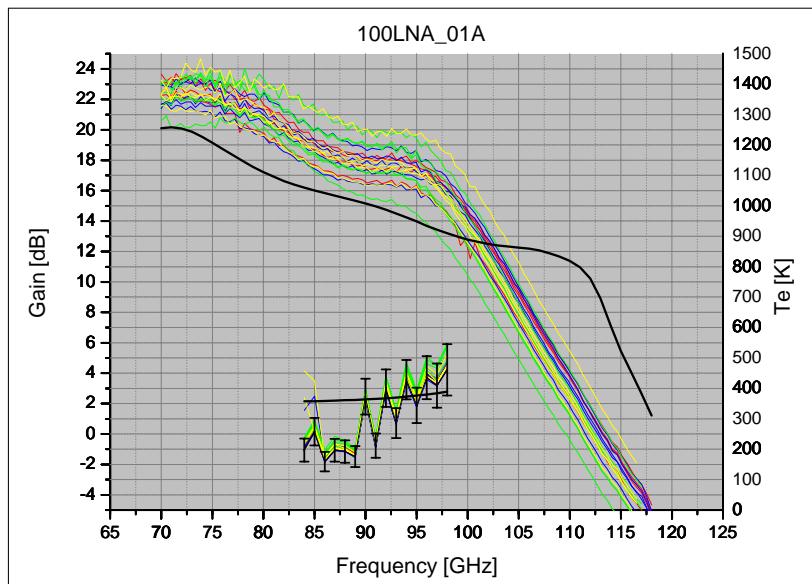


Fig 5.8.1 – 100LNA_01A Gain & Te

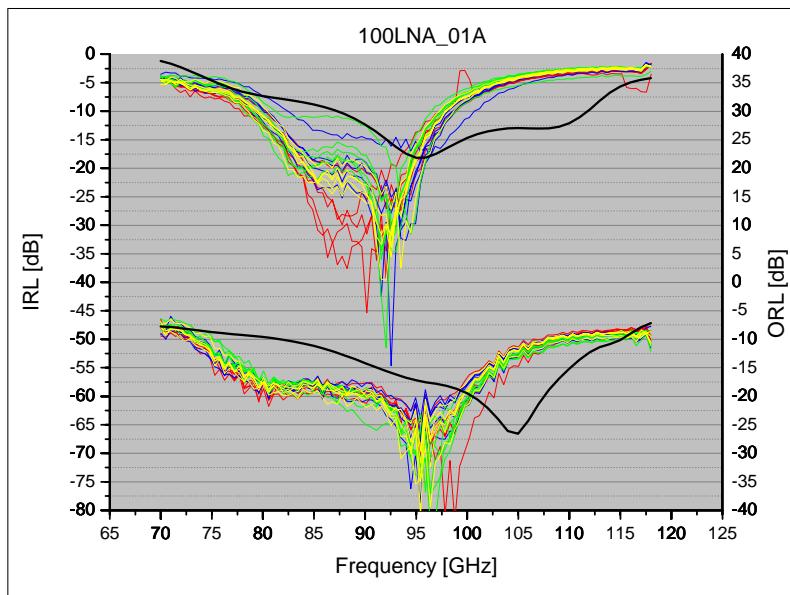


Fig 5.8.2 – 100LNA_01A IRL & ORL

■ 4245-013

■ 4245-016

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■ 4245-018

■ 4245-019

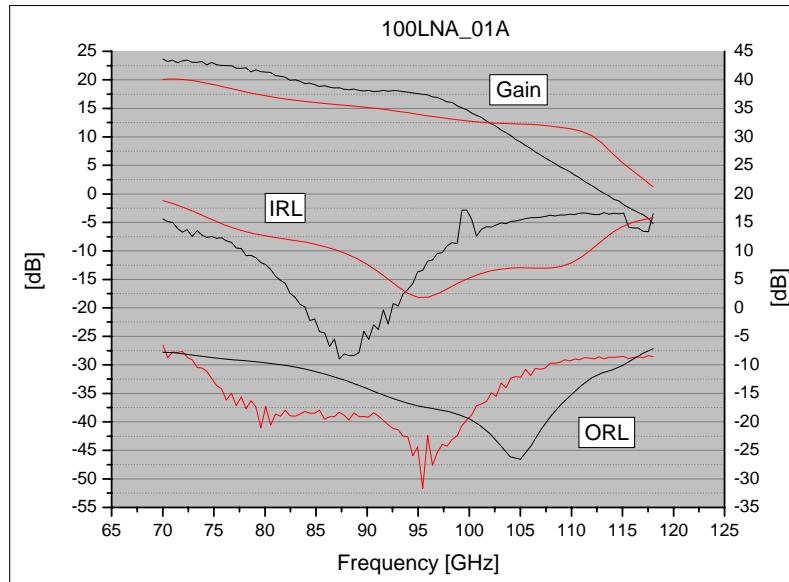


Fig 5.8.3 – 100LNA_01A Hi Resolution Gain & IRL & ORL

As described for 86LNA_01A, this device provides a narrower bandwidth than expected. Reasons could lie in devices model, which would be adjusted to work better in a different frequency range, or with higher probability, unwanted microstrip coupling at this frequencies, change too much the matching circuit behaviour. Reverse Engineering EM investigation activity will give more exhaustive explanation. This MMIC could be used between 70 to 90 GHz, accepting a 4dB slope, providing a typical gain of 20 dB. To extend the range up to 95 GHz the acceptable slope must be 5dB. Using two cascaded MMIC followed by an equaliser, we would use the resulting device up to 107 GHz providing a cooled flat gain of 25 dB.

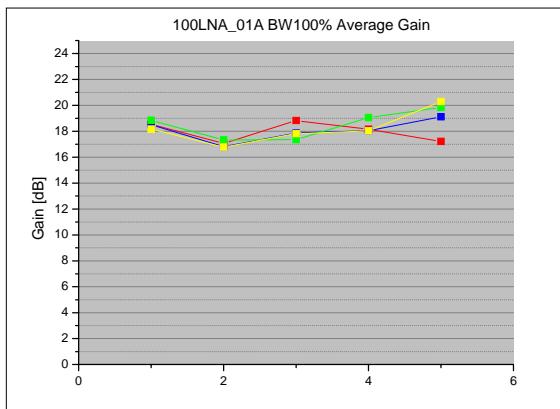


Fig 5.8.4 – 100LNA_01A BW100% Average Gain

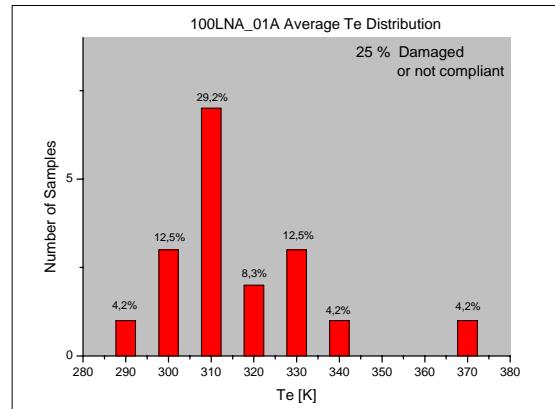


Fig 5.8.5 – 100LNA_01A Average Te distribution

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6 – Conclusion

In this report we have described an intense on wafer MMIC measurement campaign. Moreover we explained measurement methods and the preliminary consideration in order to estimate the uncertainty. This aspect is necessary especially for the Noise which is more critical than Network test and defining the uncertainty helps data interpretations. All the collected values had been analysed and cross referenced in order to obtain a precise datasheet set to describe, briefly but entirely, LNAs behaviour and characteristics. More detailed results explanation follow the datasheet set in this document. In order to conclude, we can assert that CSR18 had been a successful Wafer run. Devices are mostly suitable for radio astronomical cryogenic application in state of the art receiver system or for noise testing facilities. they are a milestone for our capability to realise receiver up to 100 GHz and an excellent starting point for future design adventure.

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Duncan Boyd – Calculate the uncertainty of NF Measurements

Patrick Robbins – Looking into Noise Figure Measurements Uncertainty

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10 - Acronym List

InP	Indium Phosphide
NGST	Northrop Grumman Space Technology
NGC	Northrop Grumman Company
HEMT	High Electron Mobility Transistor
CSIRO	Commonwealth Scientific and Industrial Research Organisation
ATNF	Australia Telescope National Facility
FARADAY	Focal plane ARRAy Design Access and Yeld
IRA	Istituto di Radioastronomia
C-TIP	CSIRO Division of Telecommunications and Industrial Physics
MMIC	Monolithic Microwave Integrated Circuit
LNA	Low Noise Amplifier
IRL	Input Return Loss
ORL	Output Return Loss
NFM	Noise Figure Meter
NS	Noise Source
ENR	Excess Noise Ratio
IL	Insertion Loss
G _{AV}	Available Gain
HTS	High Temperature Superconductor

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